

Beyond 20T: Tape characterization

D. Abraimov, J. Jaroszynski, A. Francis, Y. L. Viouchkov, J. McCallister, J. Dickey, J. DiEmmanuele, N. Gibson, H. W. Weijers, S. Hahn and D. C. Larbalestier all NHMFL

Y. Zhang SuperPower Inc.

A. Usoskin, Bruker HTS GmbH

Danko van der Laan, Advanced Conductor Technologies LLC

Plan

- Motivation
- Techniques
- Comparison $I_c(B, 4K)$ for SuperPower R&D and production line tapes
- Comparison transport properties of ReBCO tapes from different manufacturers
- Comparison high field I_c of steel coated and Cu plated tapes from SuNAM for making no-insulation magnets
- Conclusions

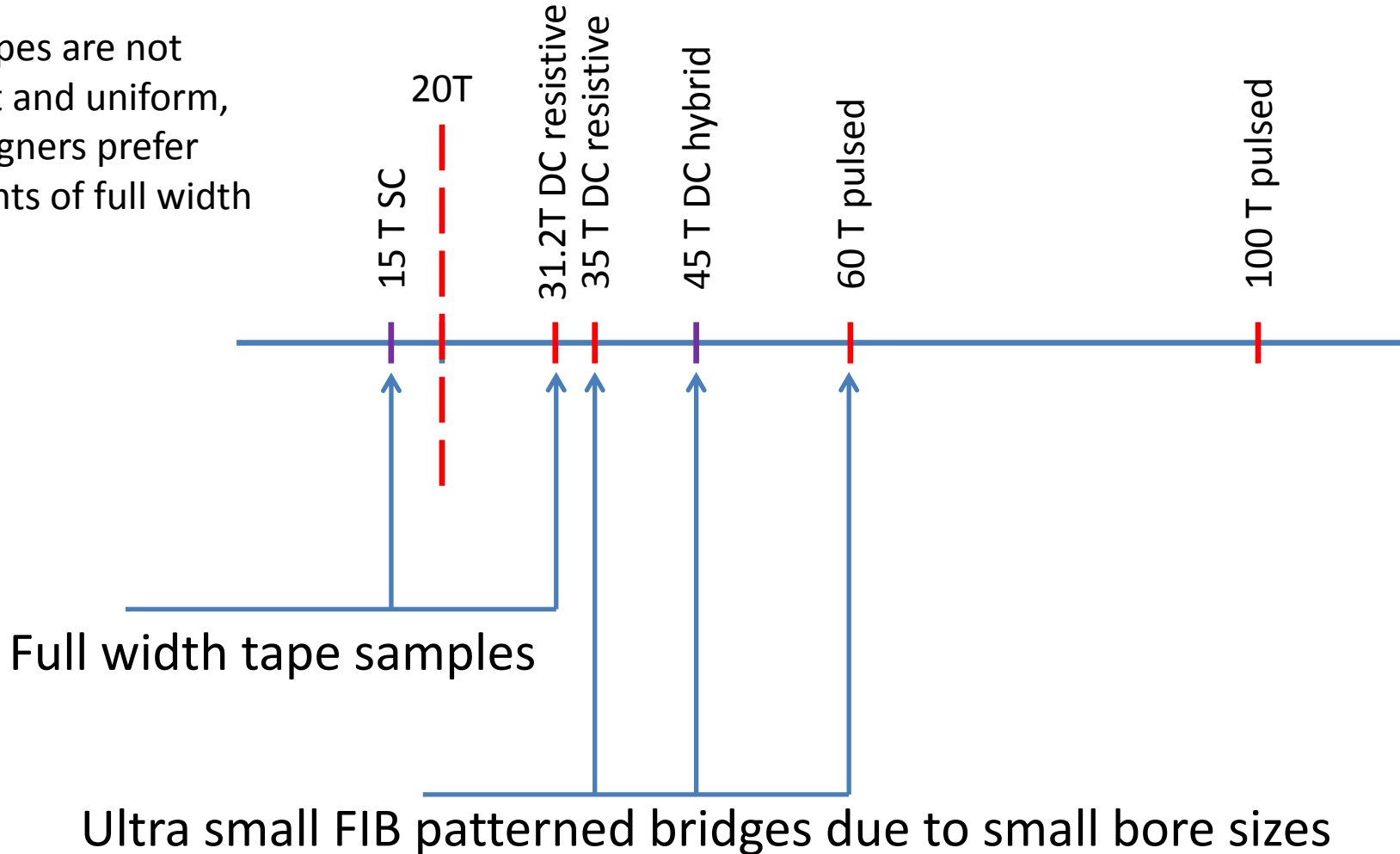
Motivation

- ReBCO superconductors become a choice material for developing all superconducting magnets capable generating ultra-high fields due to very high critical current densities in the presence of magnetic fields and high irreversibility fields
- Therefore, it is important to develop instrumentation suitable for testing I_c , J_c , f_p of ReBCO conductors in such regime
- Recent progress in introducing high concentration artificial pinning centers (APC) in ReBCO conductors makes them optimized for low-temperature high-field applications
- The understanding performance of APC at fields above 20T fields is important for solving vortex dynamics problems, conductor development, and magnet design.

Magnet systems available in NHMFL

For now resistive magnet systems available for characterization above 20T and pulsed magnets is the only choice for generating fields above 45T

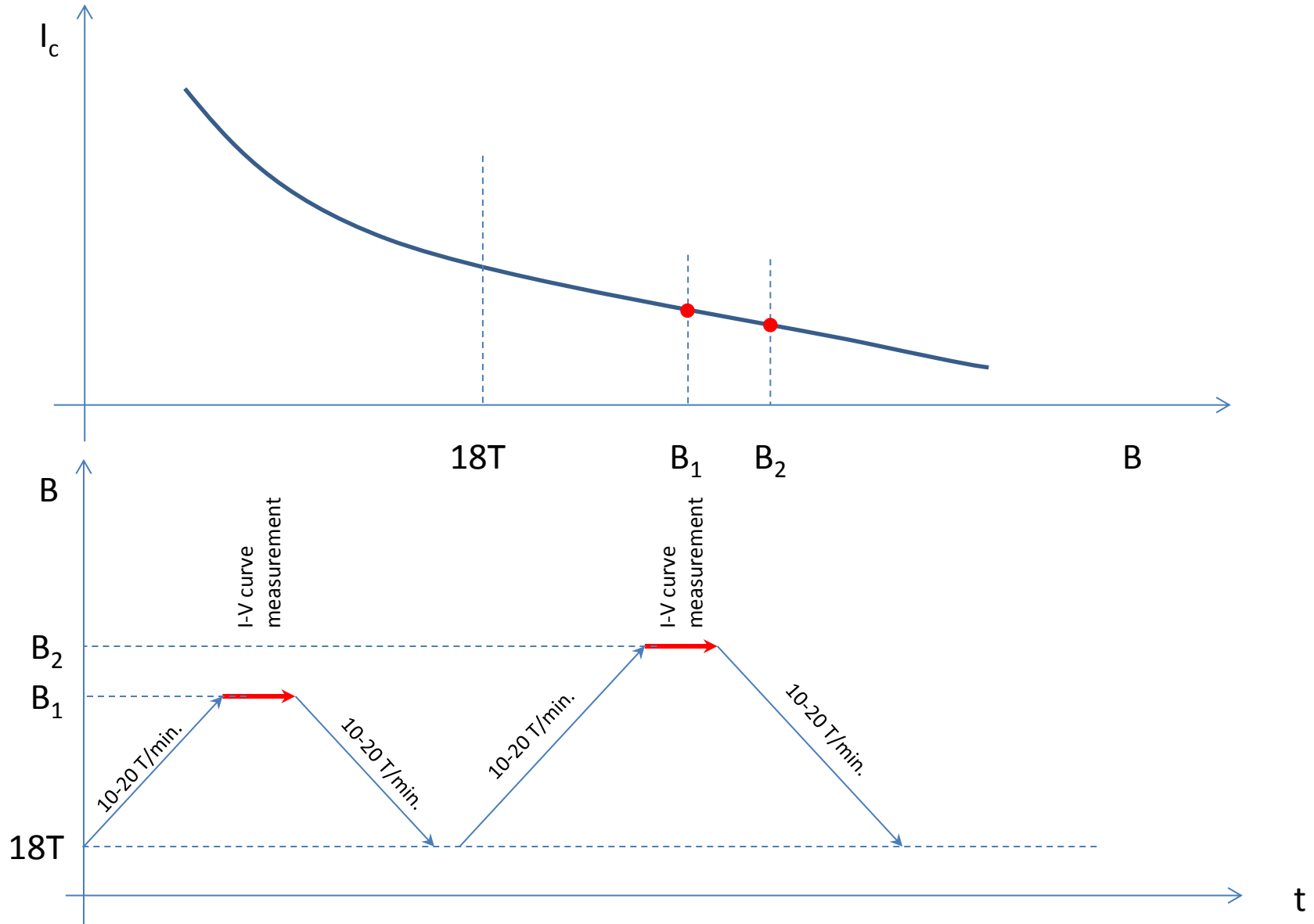
Since real tapes are not perfectly flat and uniform, magnet designers prefer measurements of full width tapes.



Main difficulties of I_c measurements above 20T

- Magnet time is seldom available since measurements in resistive magnets are more expensive than in SC ones
- In resistive magnets field is less stable as compared to SC magnets
- Due to smaller bore diameters in available resistive magnet systems sample are shorter, which mean smaller current contacts and smaller distances between current and voltage contacts, and smaller voltage criteria
- Sample heating is possible due to helium bubble problem above 20T. Mitigation this problem for full width tape samples (4mm) extends measurement time

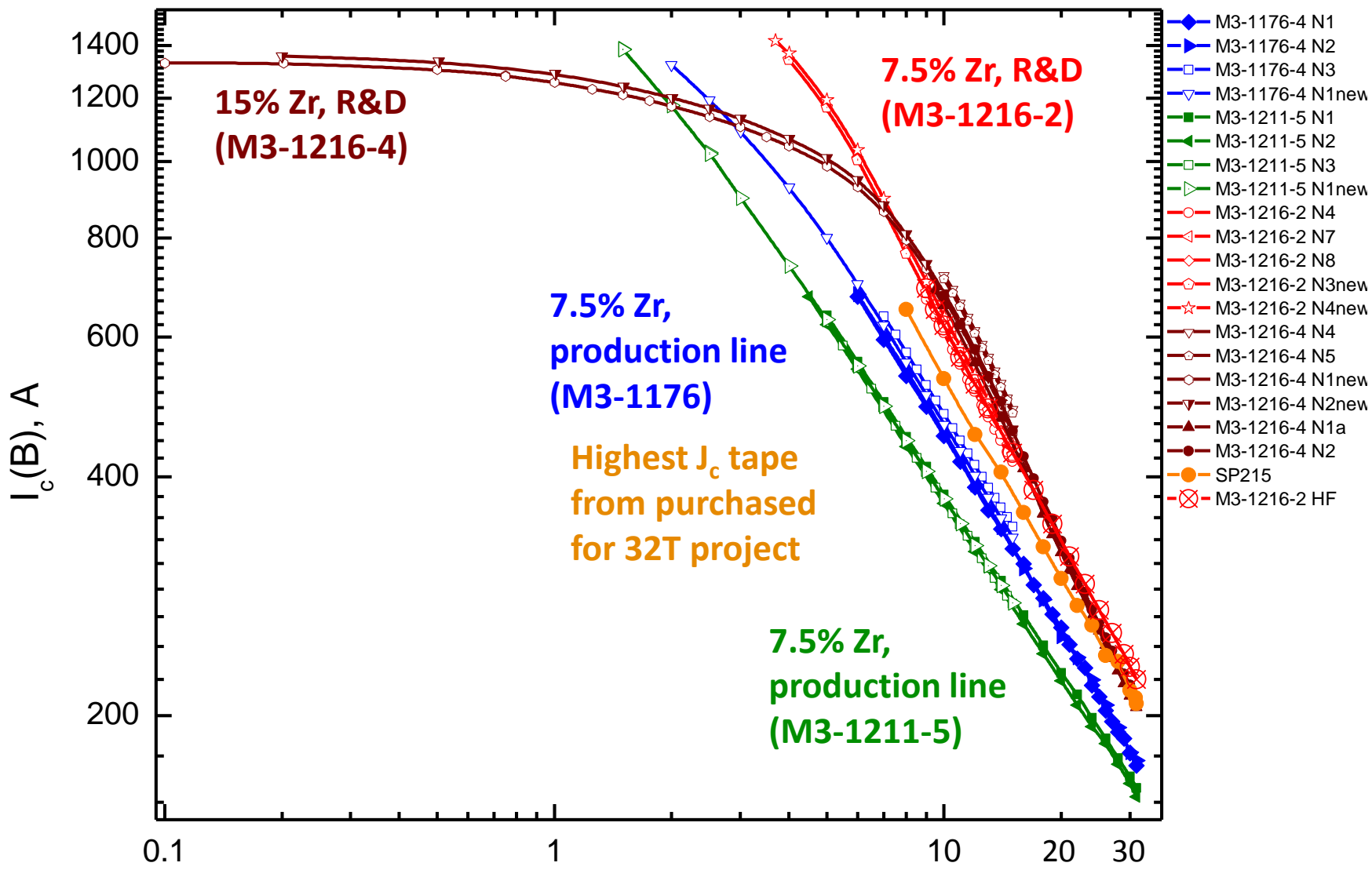
Way to mitigate helium bubble problem: measure I-V curves immediately after ramping from 18T



Comparison $I_c(B, 4K)$ for SuperPower R&D and production line tapes

Combination of $I_c(B, 4K)$ measured in resistive and superconducting magnets

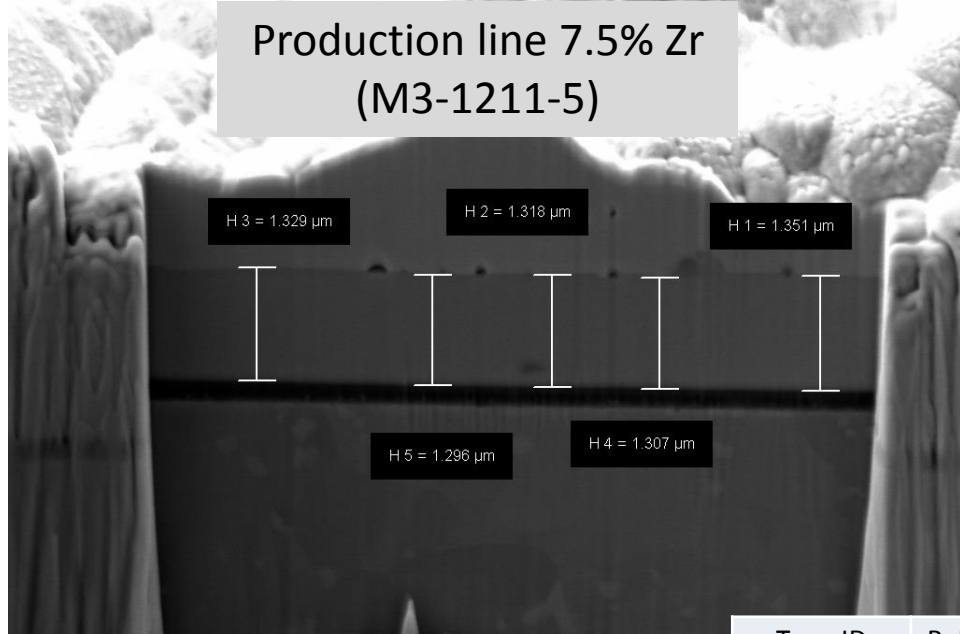
Below $\approx 2T$ 15% Zr tape has lower I_c than 7.5% Zr production line tape



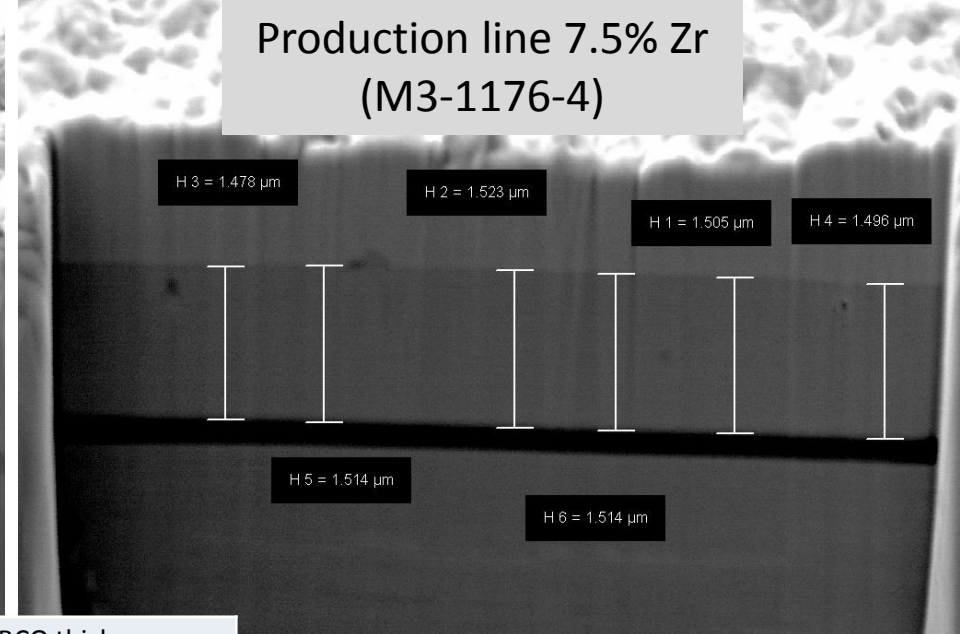
Maximum bias current is 1400A

B, T

Production line 7.5% Zr
(M3-1211-5)



Production line 7.5% Zr
(M3-1176-4)



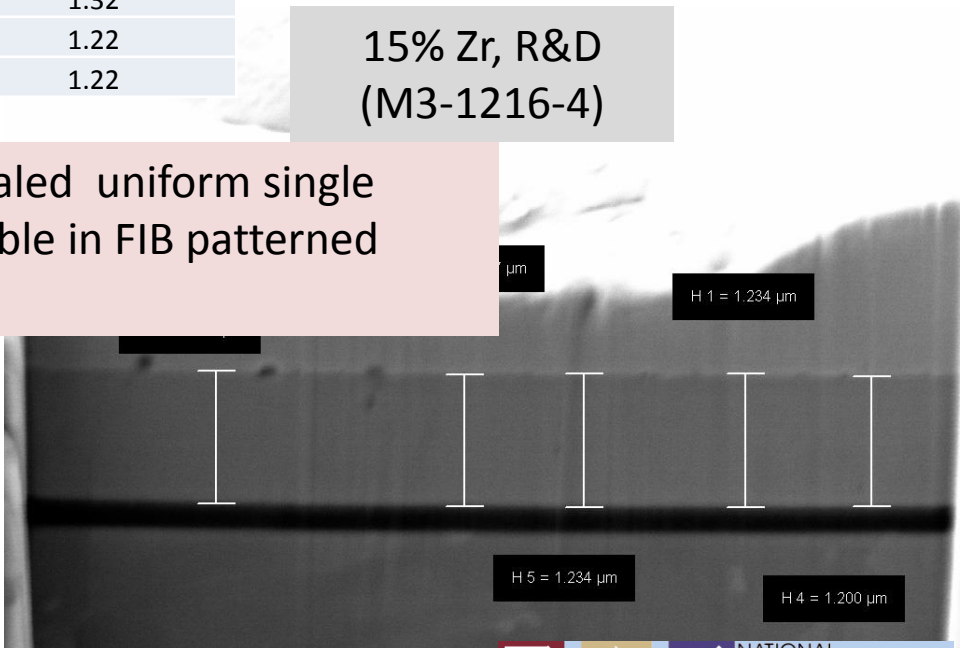
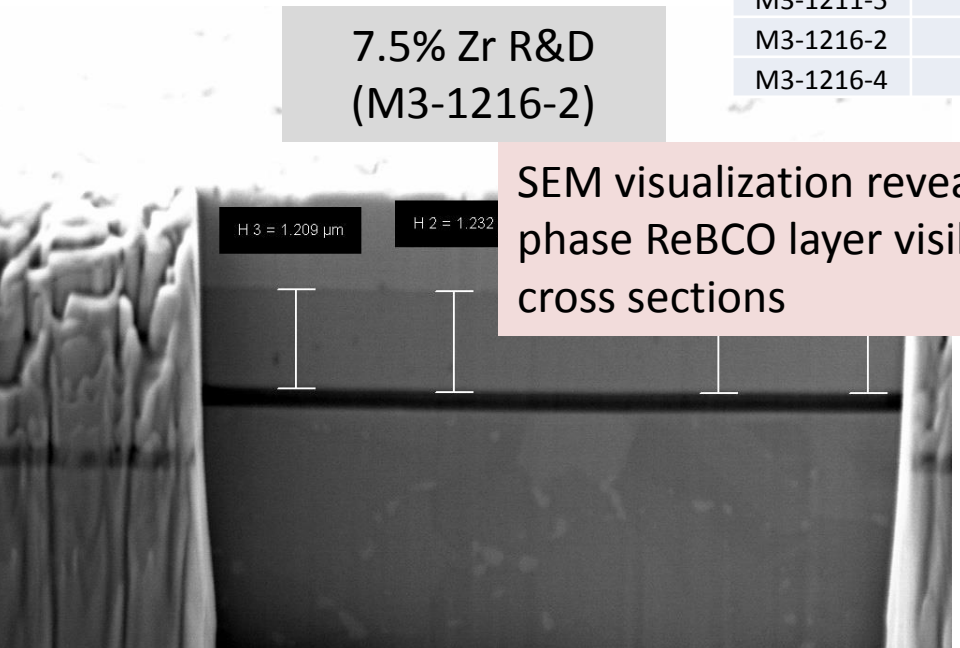
200 nm EHT = 7.00 kV FIB Mag = 26.68 K X Beam Shaft X = 0.0 % Scan Rotation = 0.0 ° Signal A =
 H Mag = 26.68 K X FIB Lock Mags = Yes Beam Shaft Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B =
 Width = 11.24 μm WD = 5.1 nm FIB Image Probe = 30KV.50 pAFIB Beam Shaft X = 0.00 nm Tilt Angle = 36.0 ° Brightnes:
 Pixel Size = 10.98 nm Aperture Size = 120.0 μm FIB Milling Probe = 30KV.50 pAFIB Beam Shaft Y = 0.00 nm Tilt Corr. = On Contrast =

Tape ID	ReBCO thickness, μm
M3-1176-4	1.50
M3-1211-5	1.32
M3-1216-2	1.22
M3-1216-4	1.22

FIB Mag = 32.90 K X Beam Shaft X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEIS 1540 XB
 FIB Lock Mags = Yes Beam Shaft Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time :20:29:21
 FIB Image Probe = 30KV.50 pAFIB Beam Shaft X = 0.00 nm Tilt Angle = 36.0 ° Brightness = 48.6 % Date :7 Dec 2016
 FIB Milling Probe = 30KV.50 pAFIB Beam Shaft Y = 0.00 nm Tilt Corr. = On Contrast = 27.4 % File Name = M3_1176_4_n1_011

7.5% Zr R&D
(M3-1216-2)

15% Zr, R&D
(M3-1216-4)



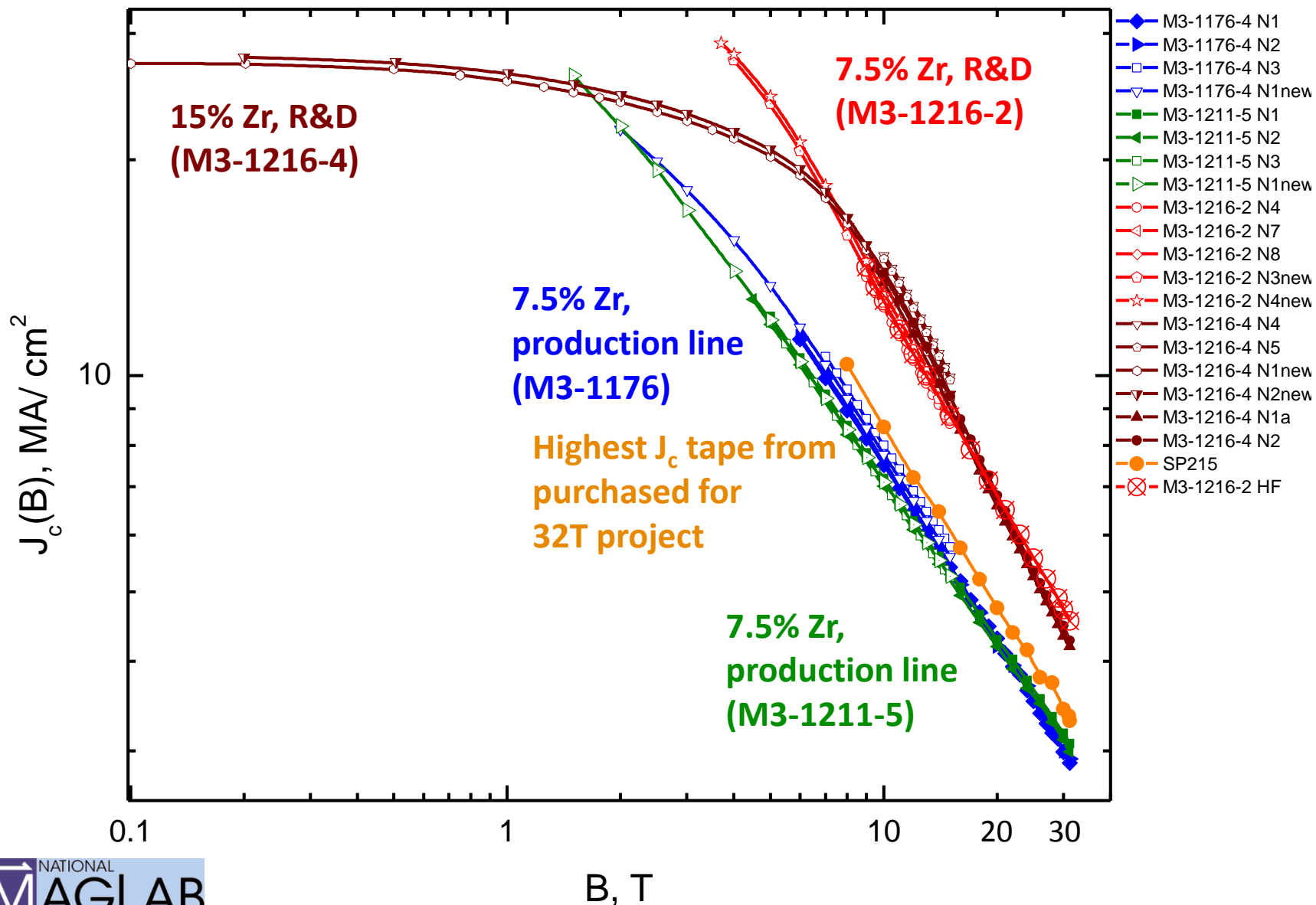
SEM visualization revealed uniform single phase ReBCO layer visible in FIB patterned cross sections

1 μm EHT = 7.00 kV FIB Mag = 25.69 K X Beam Shaft X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEIS 1540 XB
 Mag = 25.69 K X FIB Lock Mags = Yes Beam Shaft Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time :18:39:24
 Width = 11.63 μm WD = 5.1 nm FIB Image Probe = 30KV.50 pAFIB Beam Shaft X = 0.00 nm Tilt Angle = 36.0 ° Brightness = 48.6 % Date :7 Dec 2016
 Pixel Size = 11.40 nm Aperture Size = 120.0 μm FIB Milling Probe = 30KV.50 pAFIB Beam Shaft Y = 0.00 nm Tilt Corr. = On Contrast = 29.4 % File Name = SP_015.tif

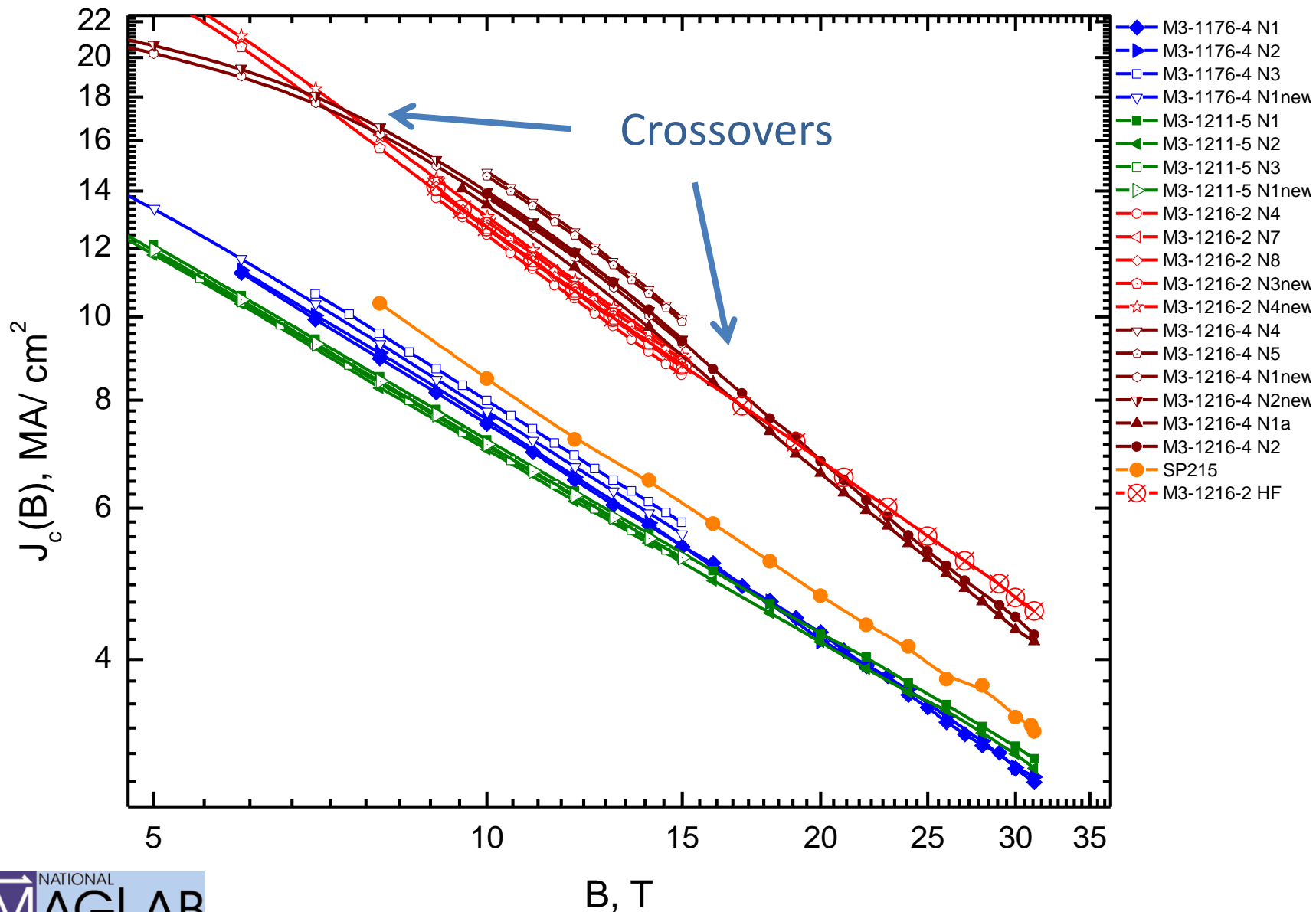
200 nm EHT = 7.00 kV FIB Mag = 33.94 K X Beam Shaft X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEIS 1540 XB
 Mag = 33.94 K X FIB Lock Mags = Yes Beam Shaft Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time :20:29:21
 Width = 8.839 μm WD = 5.1 nm FIB Image Probe = 30KV.50 pAFIB Beam Shaft X = 0.00 nm Tilt Angle = 36.0 ° Brightness = 48.6 % Date :7 Dec 2016
 Pixel Size = 8.632 nm Aperture Size = 120.0 μm FIB Milling Probe = 30KV.50 pAFIB Beam Shaft Y = 0.00 nm Tilt Corr. = On Contrast = 27.4 % File Name = M3_1176_4_n1_011



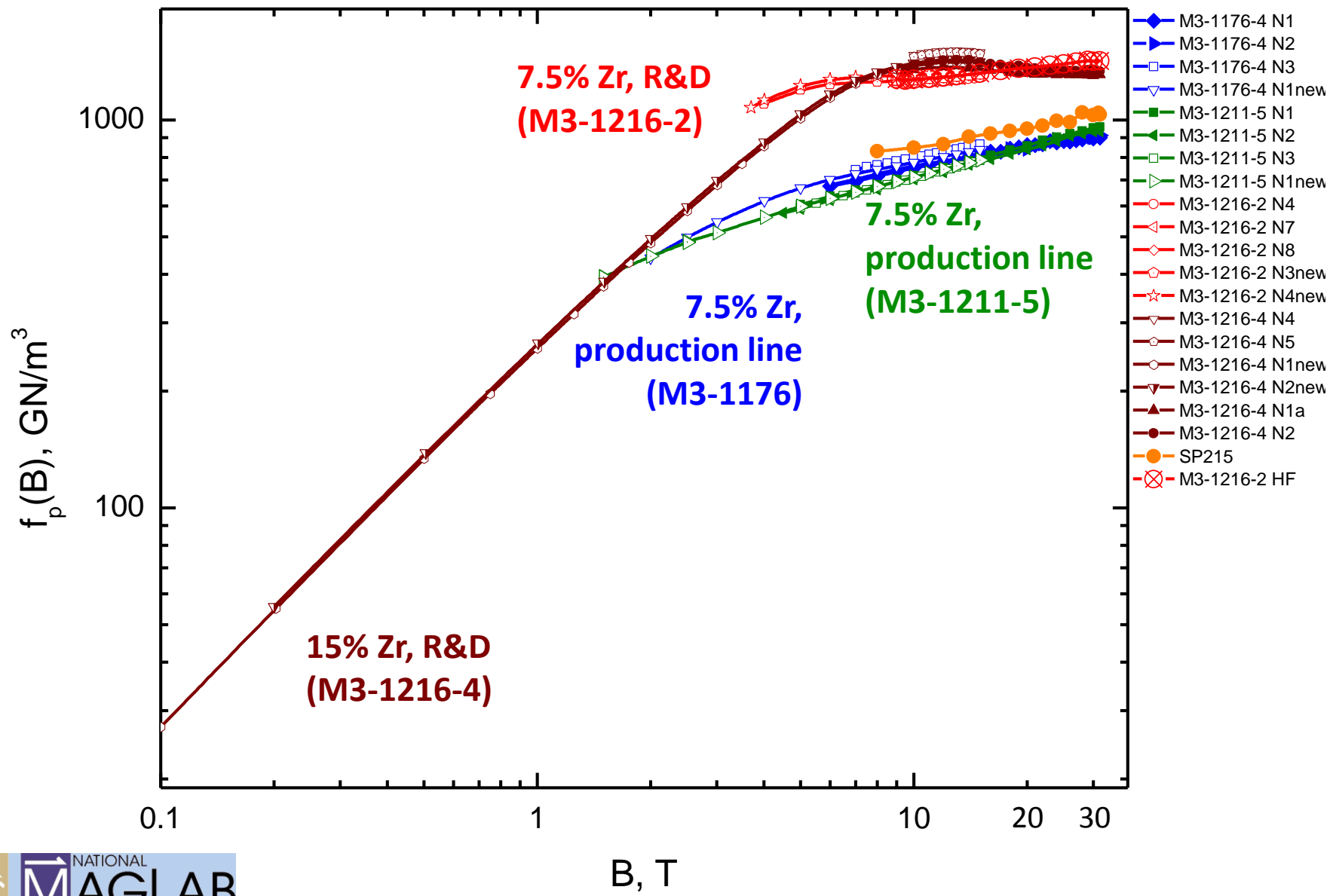
$J_c(B, 4K)$ measured in resistive and superconducting magnets



Close view: $J_c(B, 4K)$ measured in resistive and superconducting magnets

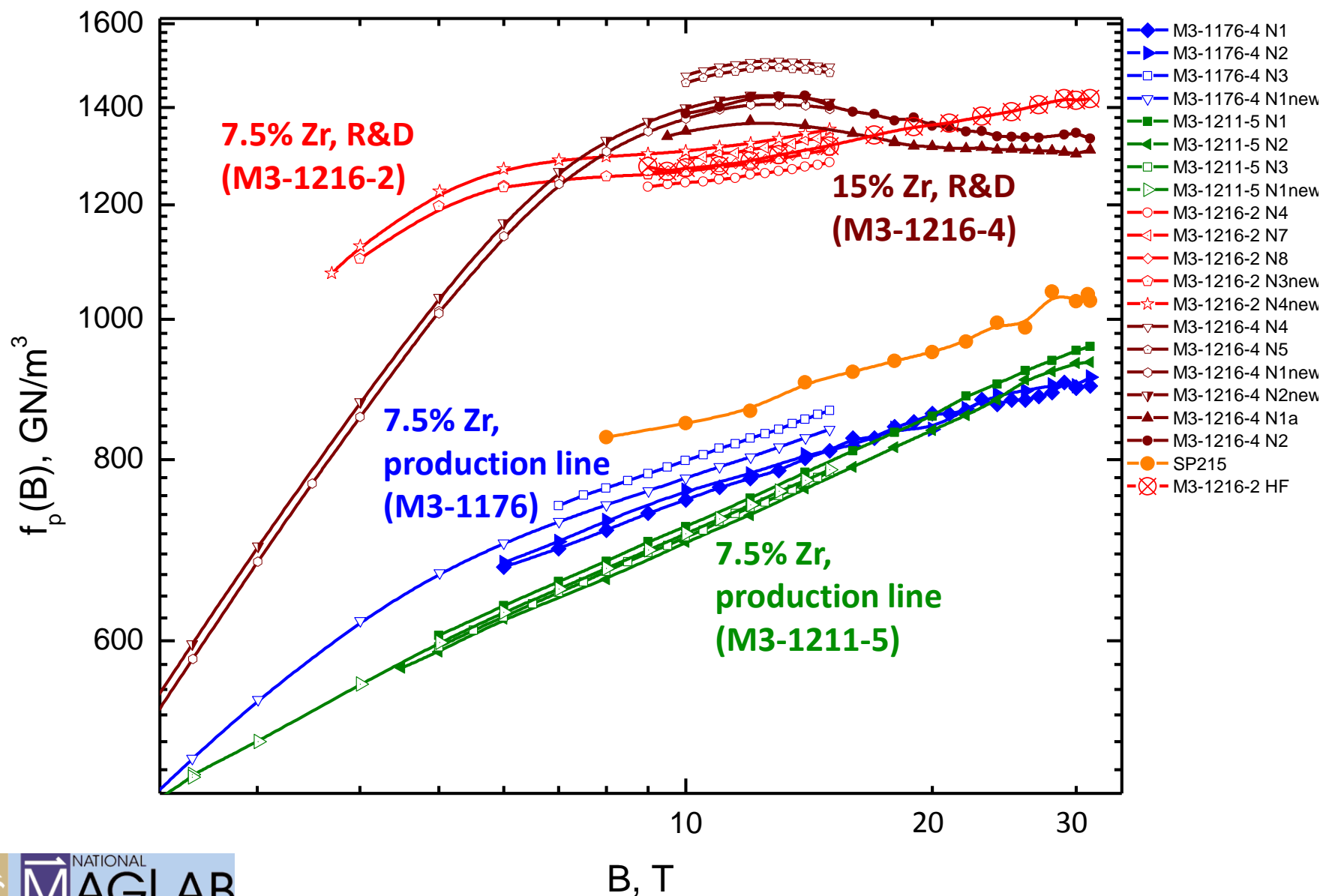


Very different values and field dependence of $f_p(B, 4.2K)$ measured for R&D and production wires in resistive magnet up to 30T



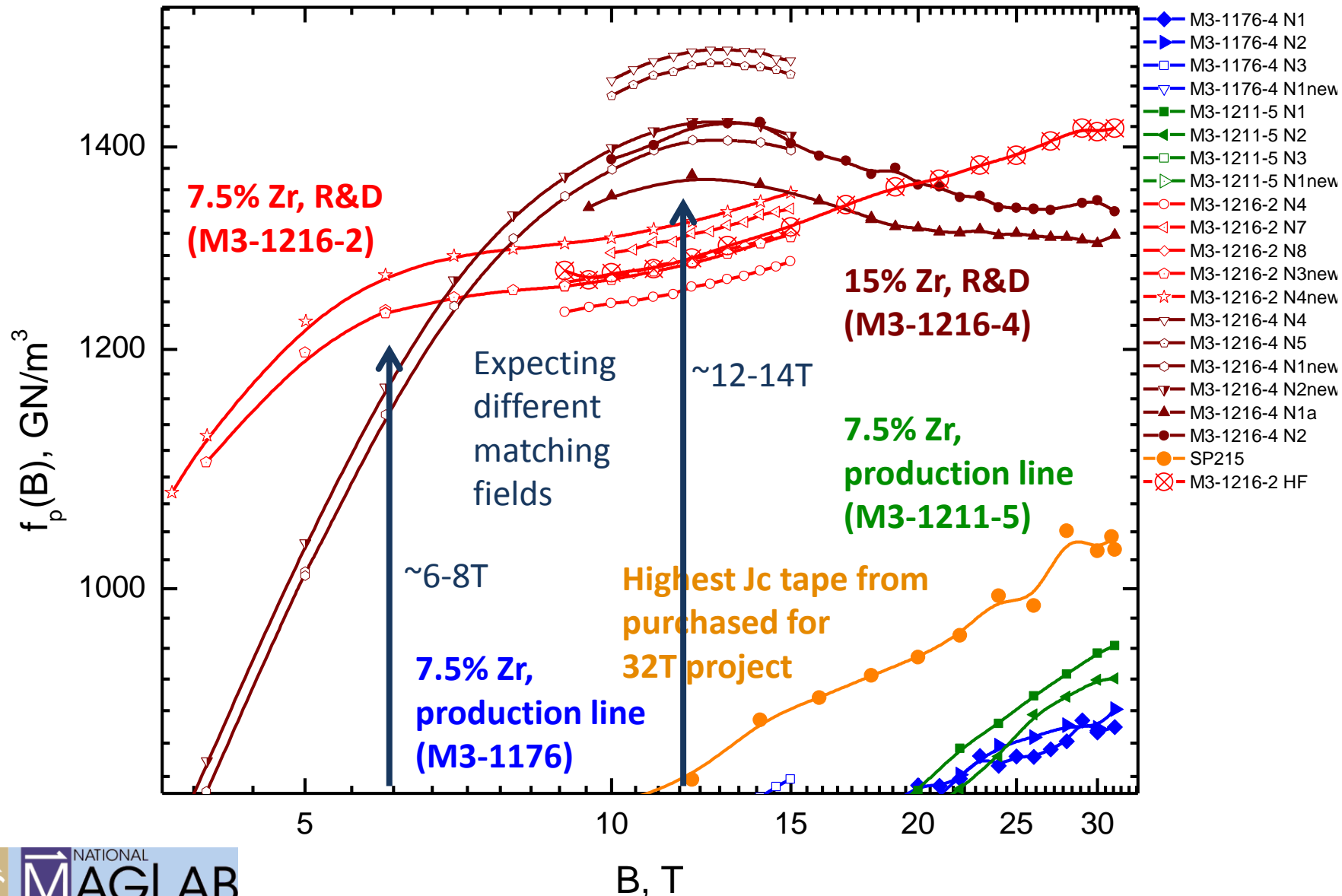
Very different values and field dependence of $f_p(B, 4.2K)$ measured for R&D and production wires in resistive magnet up to 30T

Detected crossovers in $f_p(B)$ for 7.5% , 15% Zr R&D tapes at 7-8T and 17-20T

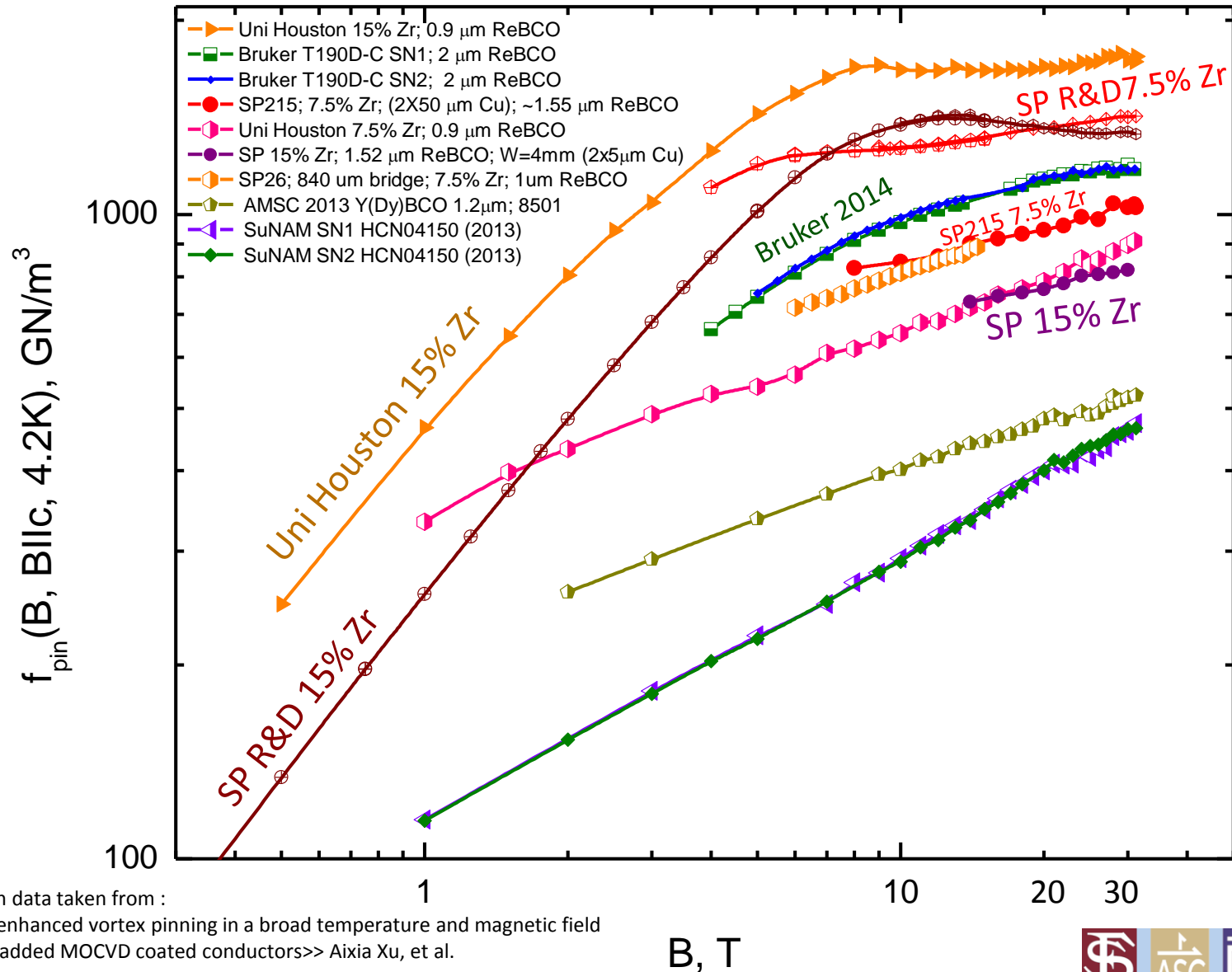


Close view: Very different values and field dependence of $f_p(B, 4.2K)$ measured for R&D and production wires in resistive magnet up to 30T

Detected crossovers in $f_p(B)$ for 7.5% , 15% Zr R&D tapes at 7-8T and 17-20T

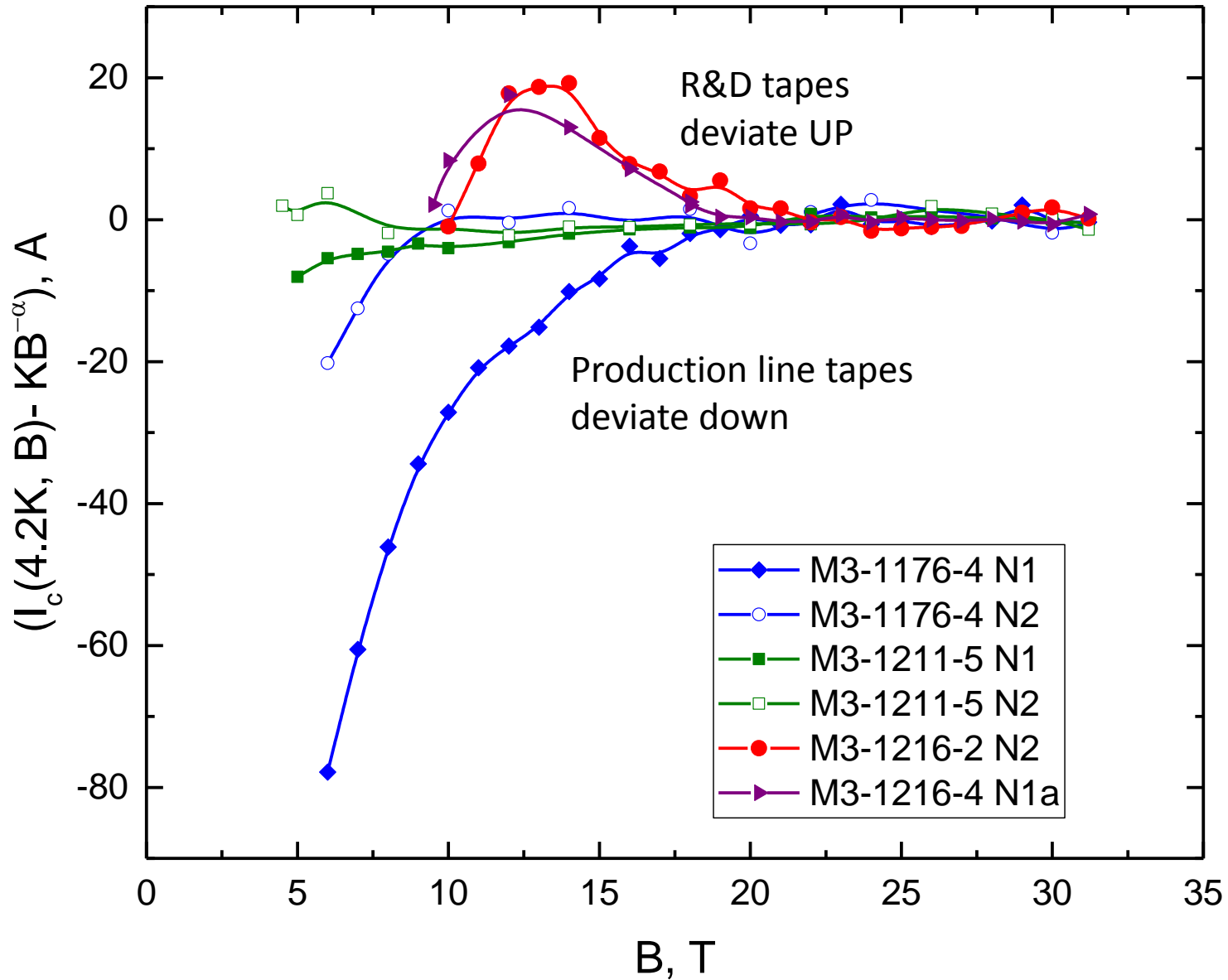


Recent SuperPower R&D tapes grown on production line are approaching Uni. Houston lab grown $f_p(B)$ values



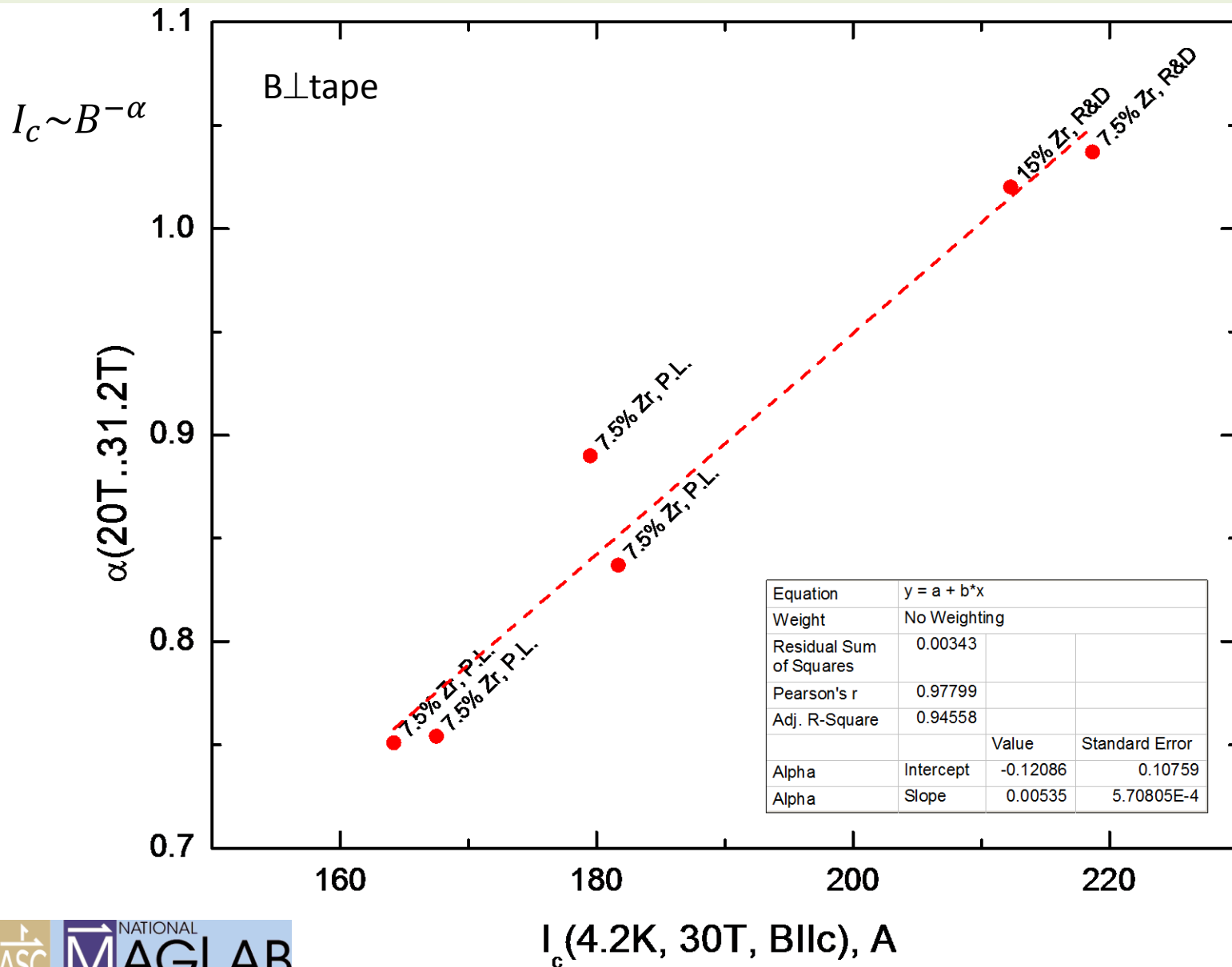
Uni Houston data taken from :
 <<Strongly enhanced vortex pinning in a broad temperature and magnetic field range of Zr-added MOCVD coated conductors>> Aixia Xu, et al.

Deviation $I_c(B)$ dependence from the fit $I_c \propto B^{-\alpha}$



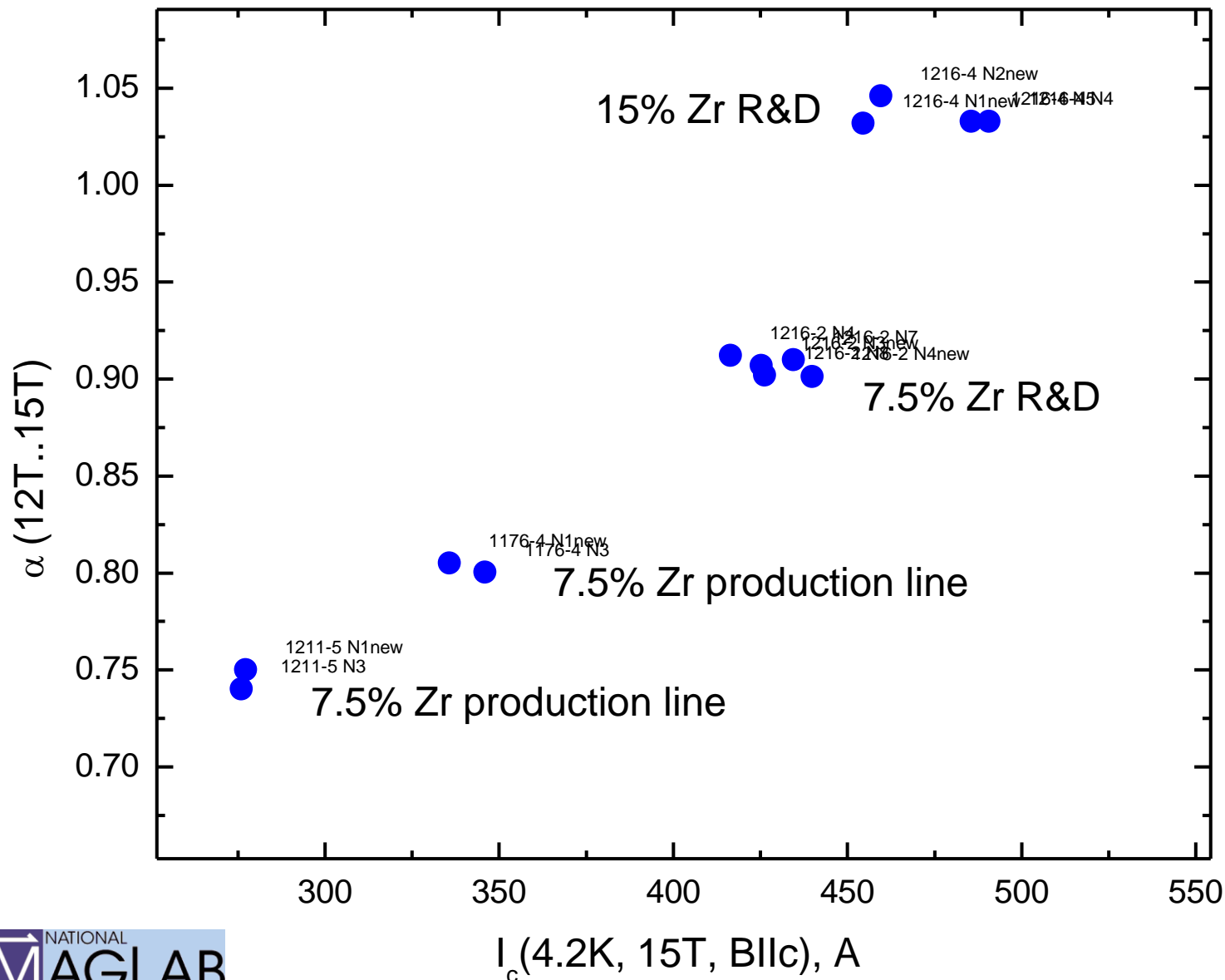
Larger α values corresponds to higher $I_c(4K, 30T)$

Interpretation: in B||c orientation larger α values correspond to larger concentration of pinning centers.



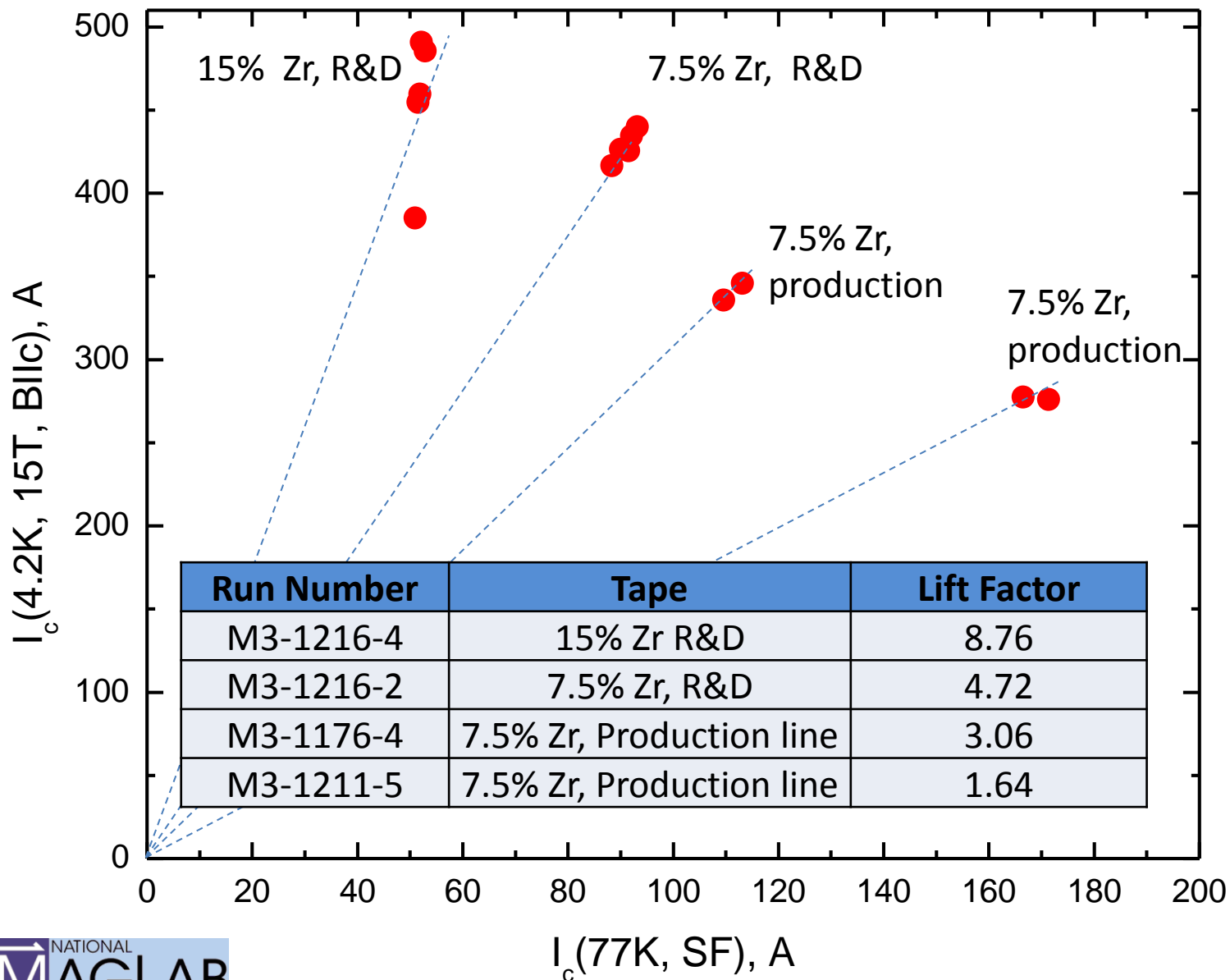
Larger α values corresponds to higher $J_c(4K, 15T)$

$$I_c \sim B^{-\alpha}$$

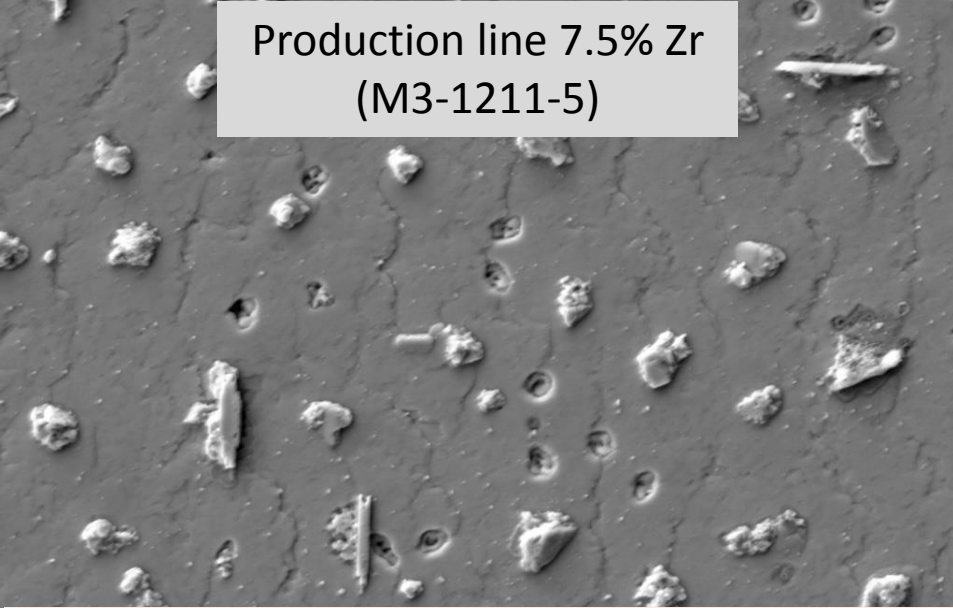


Very different lift factors for compared tapes

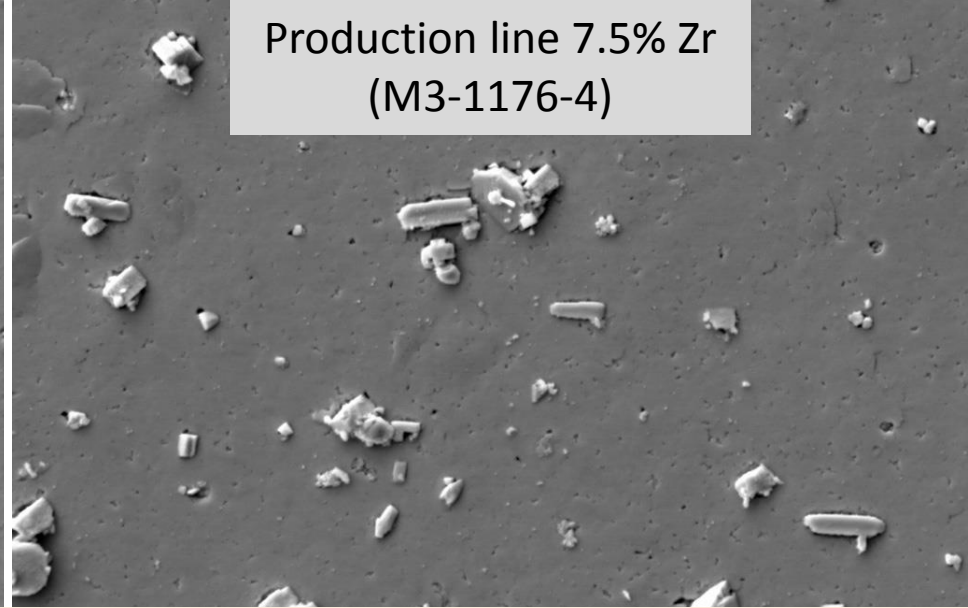
Interpretation: Additional pinning centers are not effective at 77K, SF



Production line 7.5% Zr
(M3-1211-5)

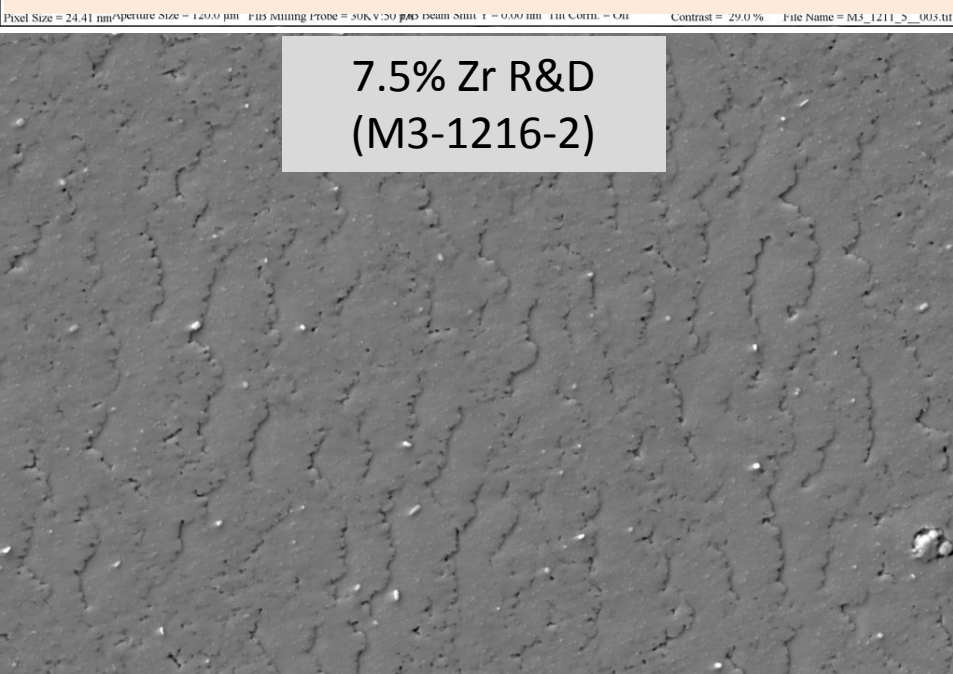


Production line 7.5% Zr
(M3-1176-4)

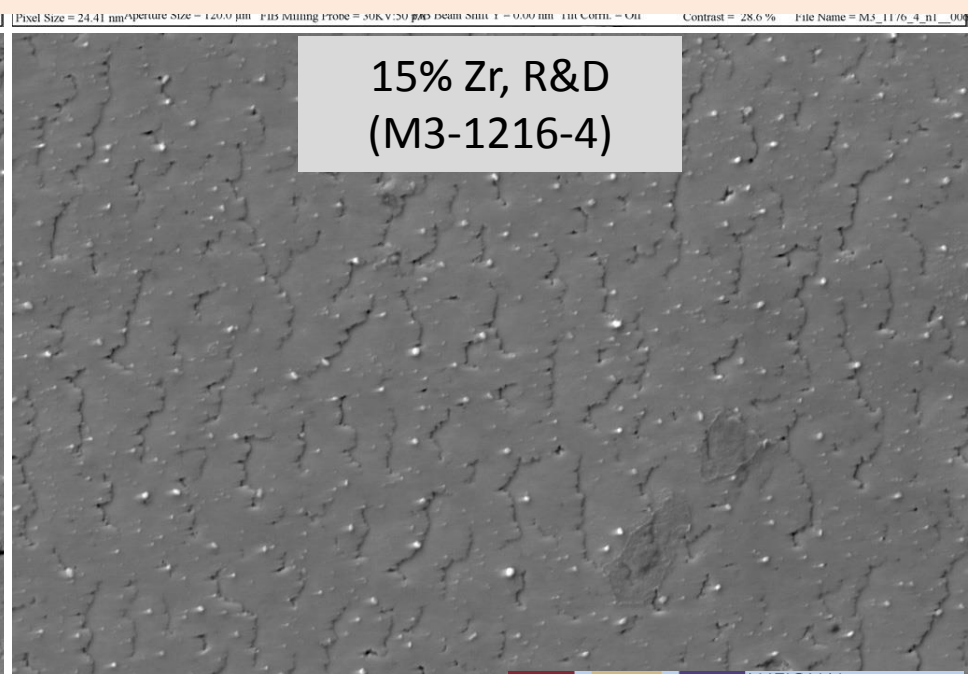


ReBCO surface of R&D tapes are free from a-axis grains and CuO grains

7.5% Zr R&D
(M3-1216-2)



15% Zr, R&D
(M3-1216-4)



Comparison transport properties of ReBCO tapes from different manufacturers

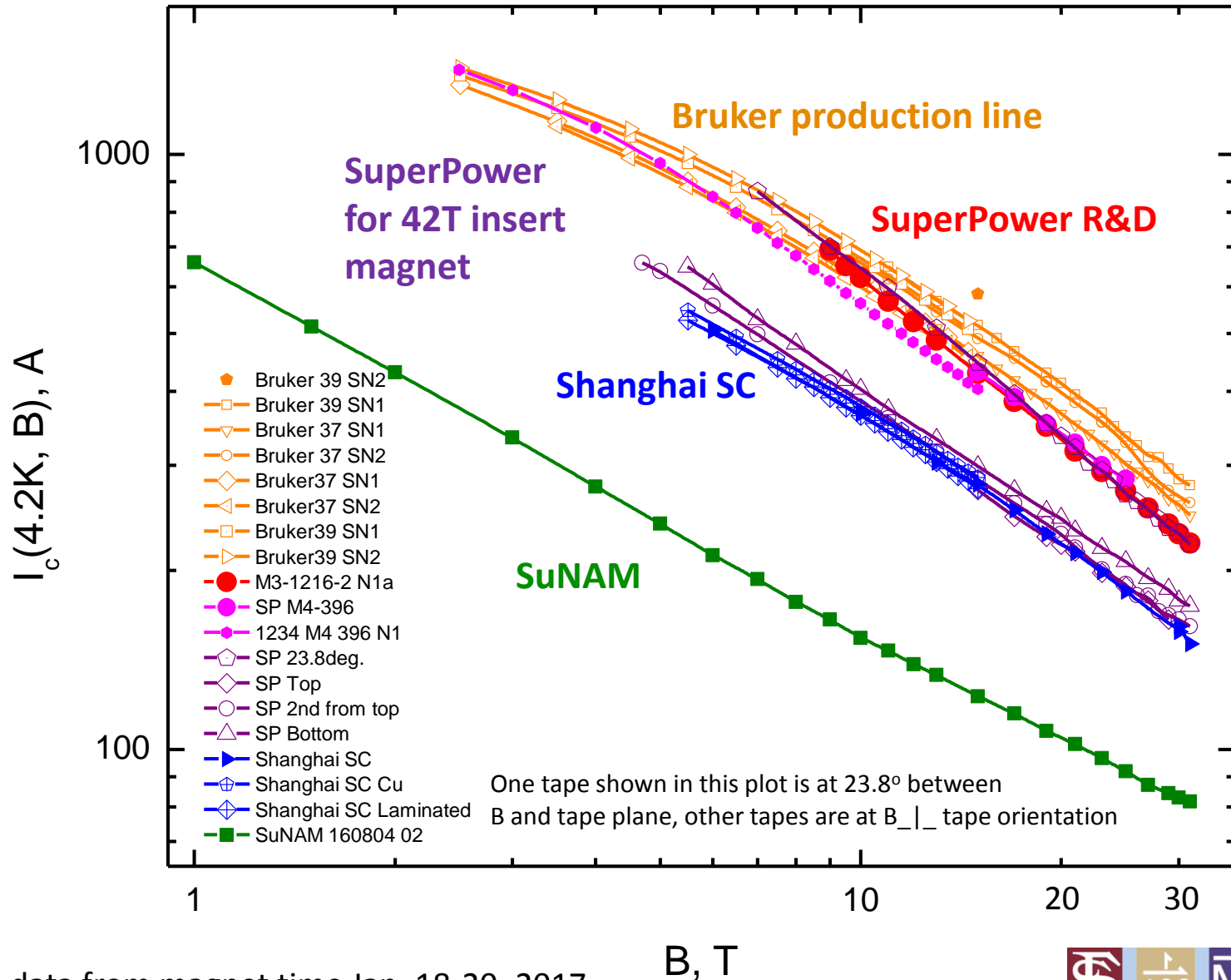


上海超导
SHANGHAI SUPERCONDUCTOR

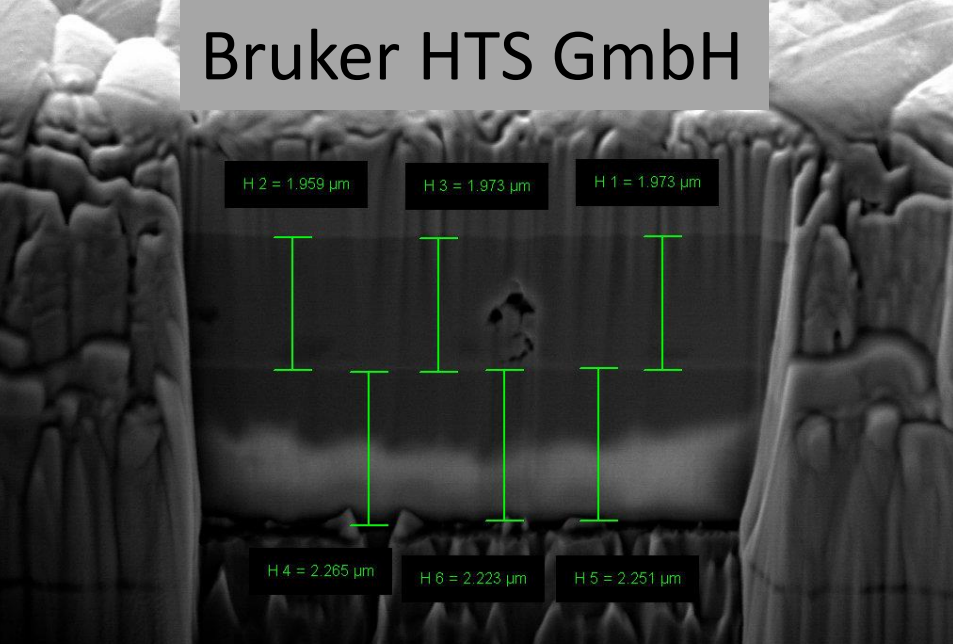


Tape	ReBCO Thickness
SP M3_1252_13	1.32
Shanghai SC	1.34
SP_42T_BottomPancake	1.42
SP_2ndFromTop	1.43
SP M4-396	1.47
SuNAM_160804_02	1.58
SuNAM_160804_01_SCN_04150	1.62
SuNAM 160819_08	1.65
Bruker39	1.82
Bruker37	1.97

Comparison transport $I_c(4.2K, B)$ for ReBCO tapes from different manufacturers
Bruker production line tapes show higher $I_c(4K, B)$ then SuperPower R&D tapes
Shanghai SC tapes show $I_c(4K, B)$ comparable to SP tapes used for 42T insert



Bruker HTS GmbH



H 2 = 1.959 μm

H 3 = 1.973 μm

H 1 = 1.973 μm

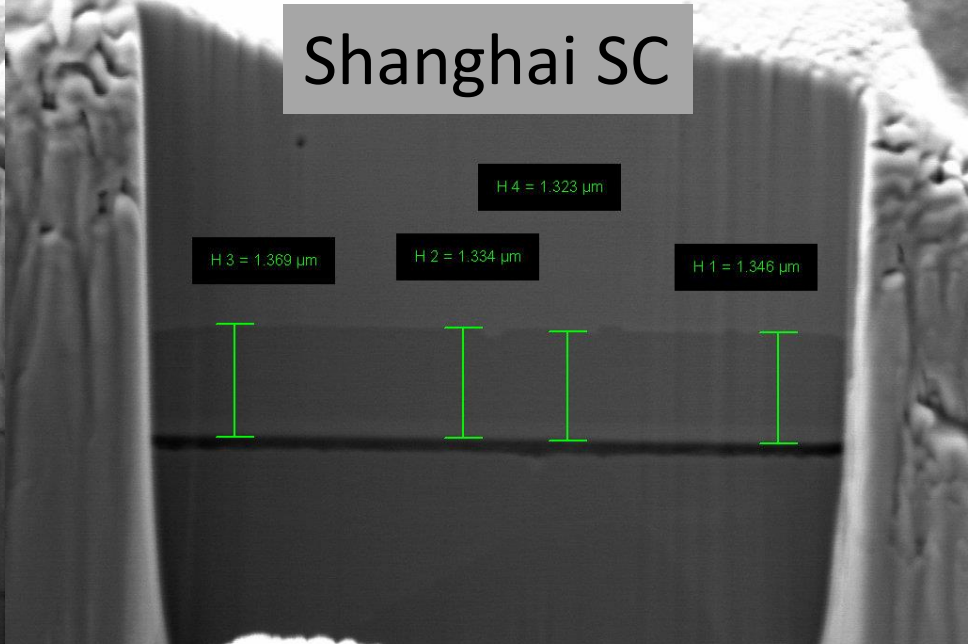
H 4 = 2.265 μm

H 6 = 2.223 μm

H 5 = 2.251 μm

1 μm
EHT = 7.00 kV FIB Mag = 21.08 K X Beam Shift X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEISS 1540 XB
Mag = 21.08 K X FIB Lock Mags = Yes Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time: 22:44:37
WD = 5.1 mm FIB Image Probe = 30KV-50 pAFIB Beam Shift X = 0.00 nm Tilt Angle = 36.0 ° Brightness = 48.4 % Date: 7 Feb 2017
Pixel Size = 13.90 nm Aperture Size = 120.0 μm FIB Milling Probe = 30KV-50 pAFIB Beam Shift Y = 0.00 nm Tilt Corr. = On Contrast = 27.7 % File Name = Bruker37_020.tif

Shanghai SC



H 3 = 1.369 μm

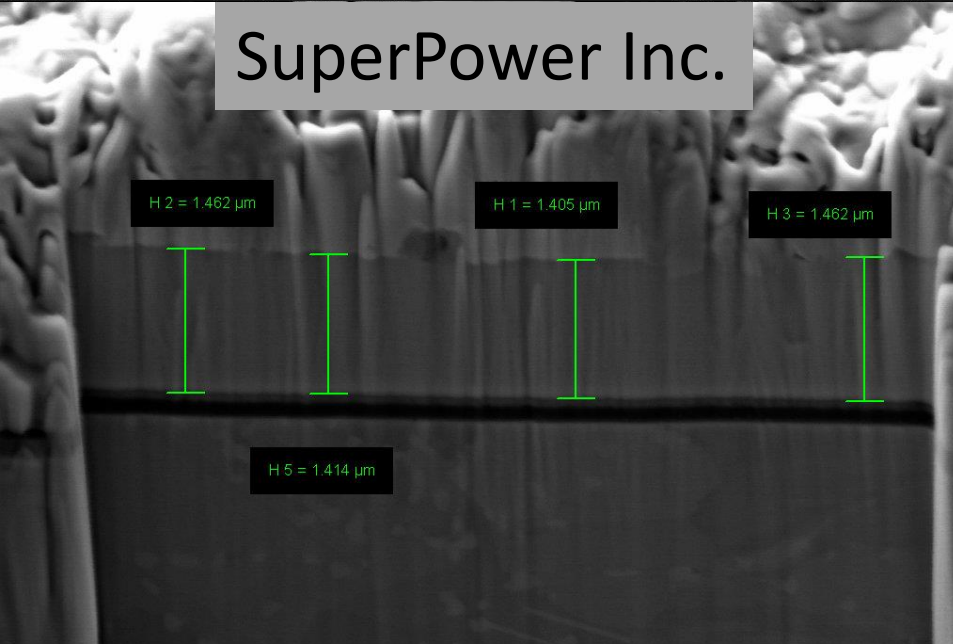
H 2 = 1.334 μm

H 1 = 1.346 μm

H 4 = 1.323 μm

1 μm
EHT = 7.00 kV FIB Mag = 25.69 K X Beam Shift X = 0.0 % Scan Rotation = 360.0 ° Signal A = SE2 ZEISS 1540 XB
Mag = 25.69 K X FIB Lock Mags = Yes Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time: 11:41:08
WD = 5.1 mm FIB Image Probe = 30KV-50 pAFIB Beam Shift X = 0.00 nm Tilt Angle = 36.0 ° Brightness = 48.6 % Date: 9 Feb 2017
Pixel Size = 11.63 nm Aperture Size = 120.0 μm FIB Milling Probe = 30KV-50 pAFIB Beam Shift Y = 0.00 nm Tilt Corr. = On Contrast = 29.3 % File Name = Shanghai_SC020.tif

SuperPower Inc.



H 2 = 1.462 μm

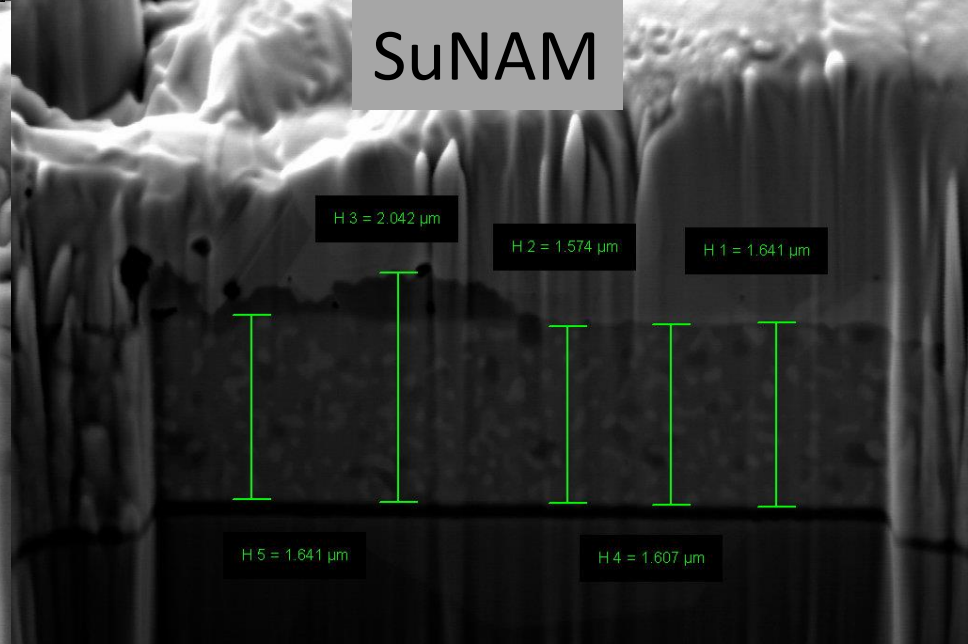
H 1 = 1.405 μm

H 3 = 1.462 μm

H 5 = 1.414 μm

200 nm
EHT = 7.00 kV FIB Mag = 30.65 K X Beam Shift X = 0.0 % Scan Rotation = 357.0 ° Signal A = SE2 ZEISS 1540 XB
Mag = 30.65 K X FIB Lock Mags = Yes Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time: 15:24:32
WD = 5.1 mm FIB Image Probe = 30KV-50 pAFIB Beam Shift X = 0.00 nm Tilt Angle = 36.0 ° Brightness = 48.6 % Date: 10 Feb 2017
Pixel Size = 9.57 nm Aperture Size = 120.0 μm FIB Milling Probe = 30KV-50 pAFIB Beam Shift Y = 0.00 nm Tilt Corr. = On Contrast = 28.4 % File Name = SuperPower_2nd front.tif

SuNAM



H 3 = 2.042 μm

H 2 = 1.574 μm

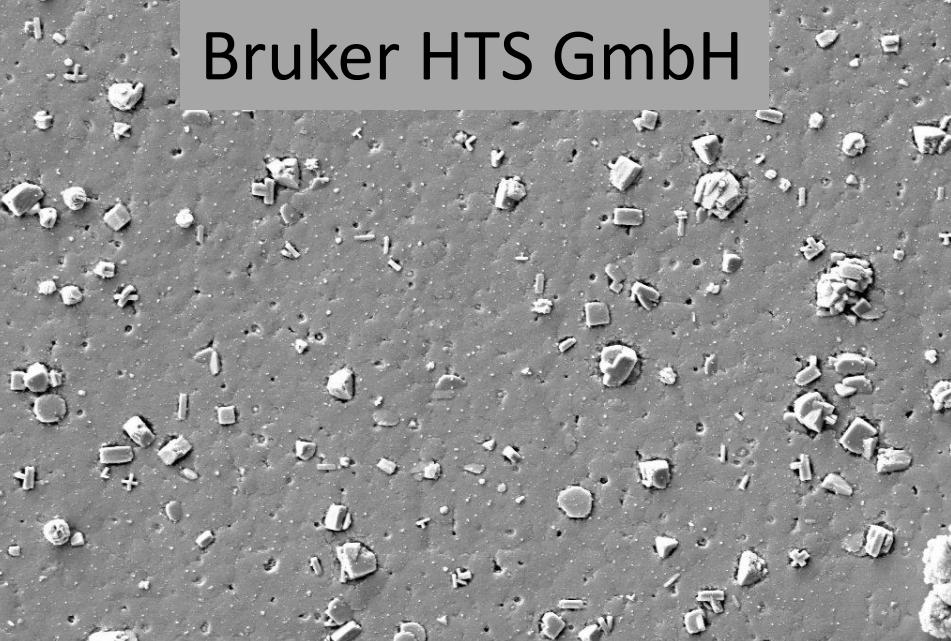
H 1 = 1.641 μm

H 5 = 1.641 μm

H 4 = 1.607 μm

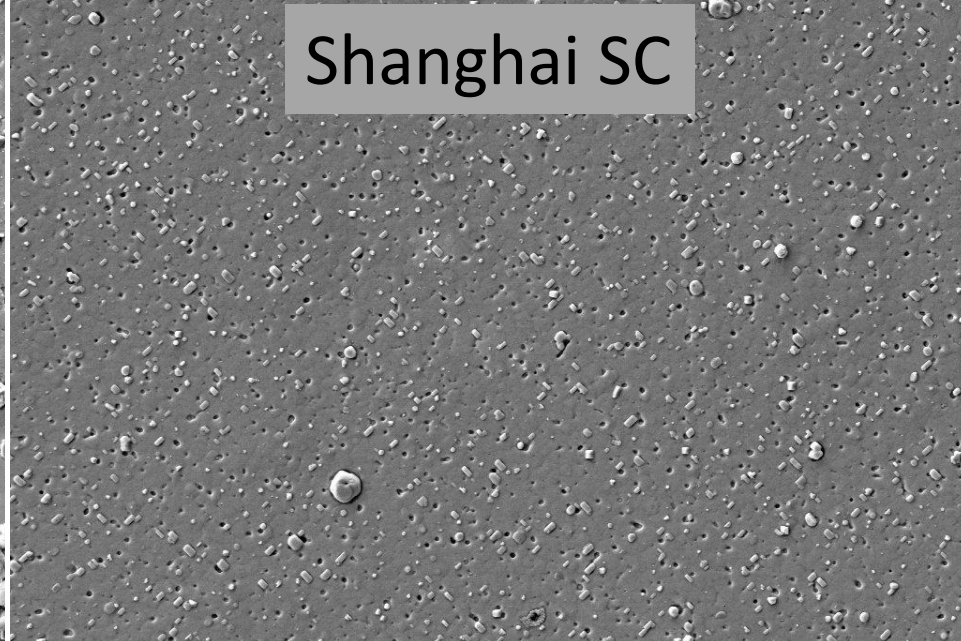
200 nm
EHT = 7.00 kV FIB Mag = 35.00 K X Beam Shift X = 0.0 % Scan Rotation = 355.0 ° Signal A = SE2 ZEISS 1540 XB
Mag = 35.00 K X FIB Lock Mags = Yes Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time: 17:19:45
WD = 5.1 mm FIB Image Probe = 30KV-50 pAFIB Beam Shift X = 0.00 nm Tilt Angle = 36.0 ° Brightness = 48.3 % Date: 9 Feb 2017
Pixel Size = 8.371 nm Aperture Size = 120.0 μm FIB Milling Probe = 30KV-50 pAFIB Beam Shift Y = 0.00 nm Tilt Corr. = On Contrast = 27.9 % File Name = SuNAM_160804_01.tif

Bruker HTS GmbH



1 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEIS 1540 XE
Mag = 6.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 21:07:22
Width = 50.00 μ m WD = 10.0 mm FIB Image Probe = 30KV-50 pA/FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.4 % Date 7 Feb 2017
Pixel Size = 48.83 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA/FIB Beam Shift Y = 0.00 nm Tilt Corn. = Off Contrast = 30.6 % File Name = Bruker37_011.tif

Shanghai SC



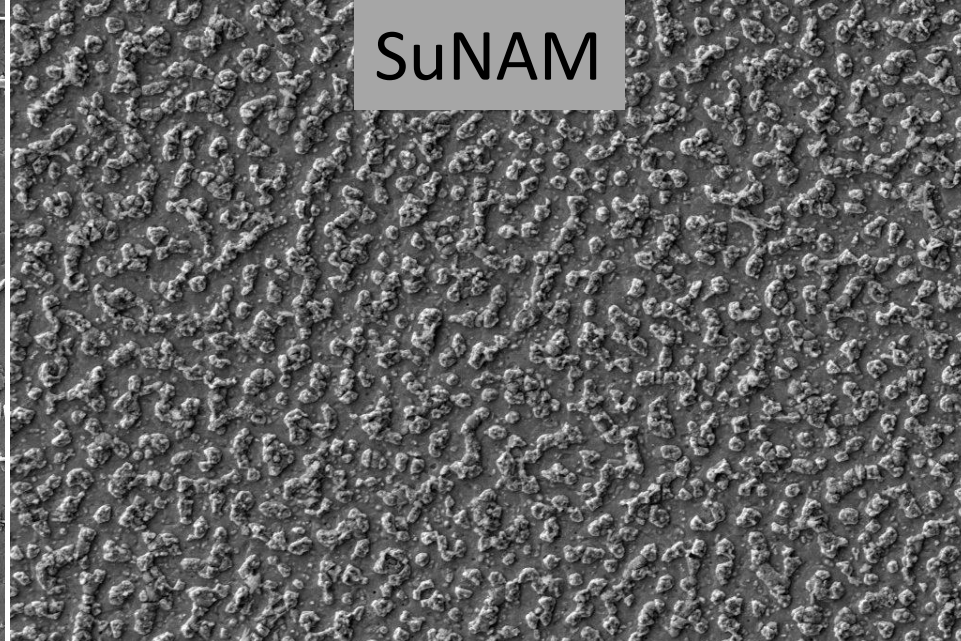
1 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEIS 1540 XE
Mag = 6.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 22:37:47
Width = 50.00 μ m WD = 10.0 mm FIB Image Probe = 30KV-50 pA/FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.3 % Date 7 Feb 2017
Pixel Size = 48.83 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA/FIB Beam Shift Y = 0.00 nm Tilt Corn. = Off Contrast = 29.7 % File Name = ShanghaiSC_003.tif

SuperPower Inc.



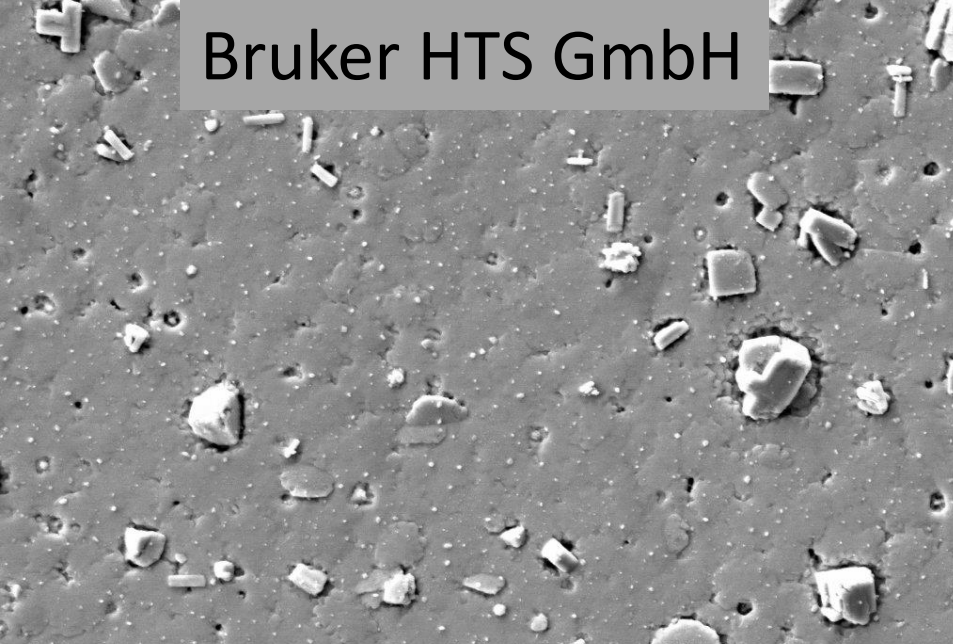
1 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 358.0 ° Signal A = SE2 ZEIS 1540 XE
Mag = 6.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 14:28:15
Width = 50.00 μ m WD = 10.0 mm FIB Image Probe = 30KV-50 pA/FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.6 % Date 10 Feb 2017
Pixel Size = 48.83 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA/FIB Beam Shift Y = 0.00 nm Tilt Corn. = Off Contrast = 28.9 % File Name = SuperPower_2nd_fro

SuNAM



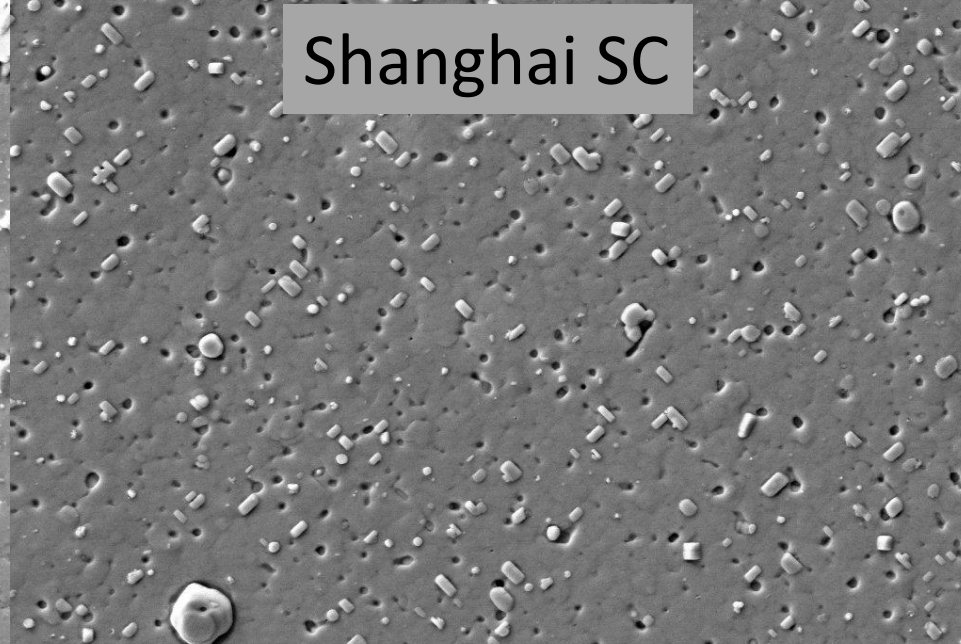
2 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 355.0 ° Signal A = SE2 ZEIS 1540 XE
Mag = 6.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 16:15:50
Width = 50.00 μ m WD = 10.0 mm FIB Image Probe = 30KV-50 pA/FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.3 % Date 9 Feb 2017
Pixel Size = 48.83 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA/FIB Beam Shift Y = 0.00 nm Tilt Corn. = Off Contrast = 28.6 % File Name = SuNAM_160804_01

Bruker HTS GmbH



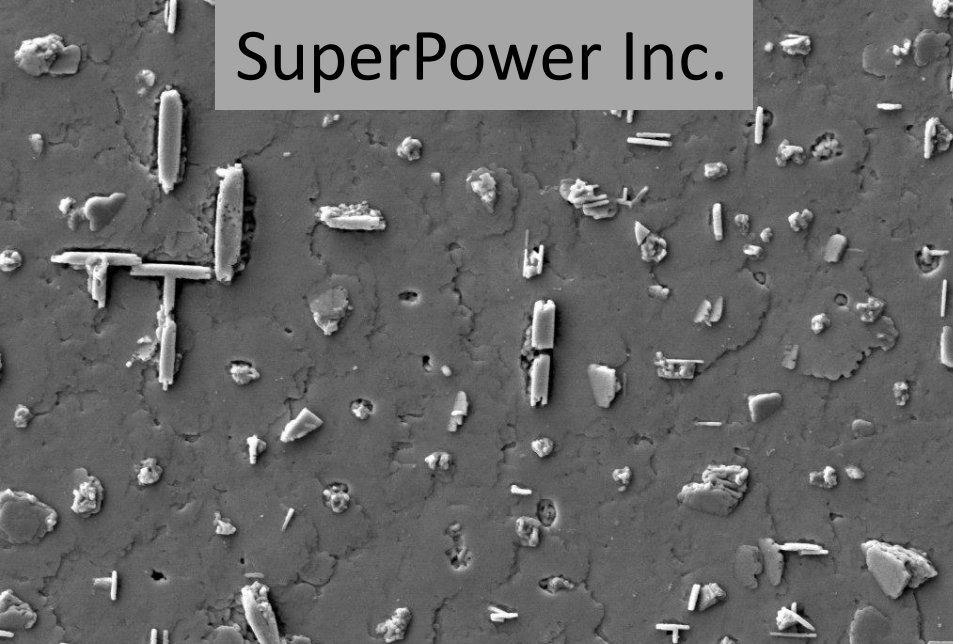
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Mag = 12.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 21:06:46
WD = 10.0 mm FIB Image Probe = 30KV-50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.4 % Date 7 Feb 2017
Pixel Size = 24.41 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 30.6 % File Name = Bruker37_010.tif

Shanghai SC



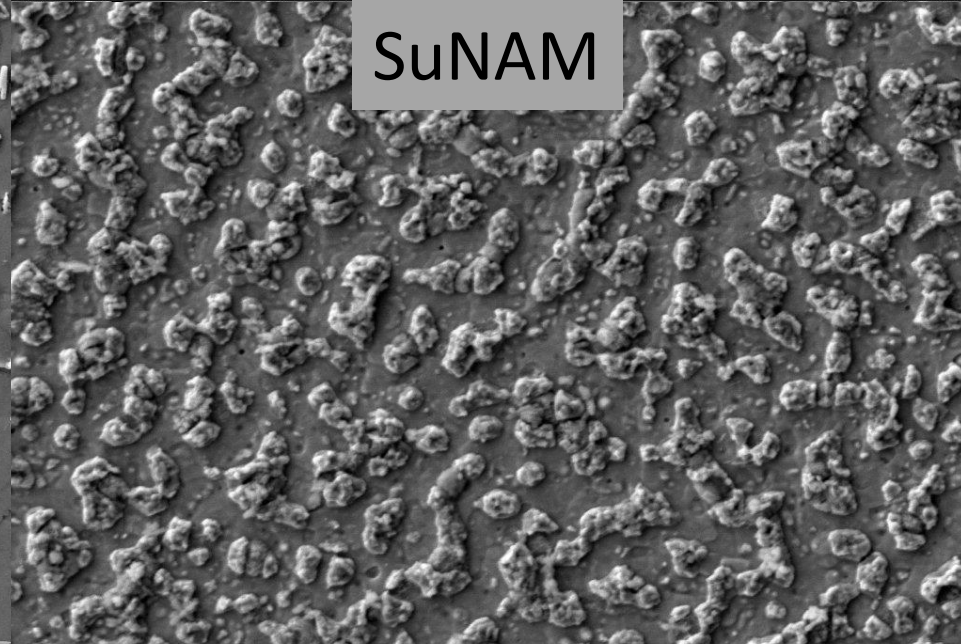
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Mag = 12.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 22:58:07
WD = 10.0 mm FIB Image Probe = 30KV-50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.3 % Date 7 Feb 2017
Pixel Size = 24.41 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 29.7 % File Name = ShanghasSC_004.tif

SuperPower Inc.



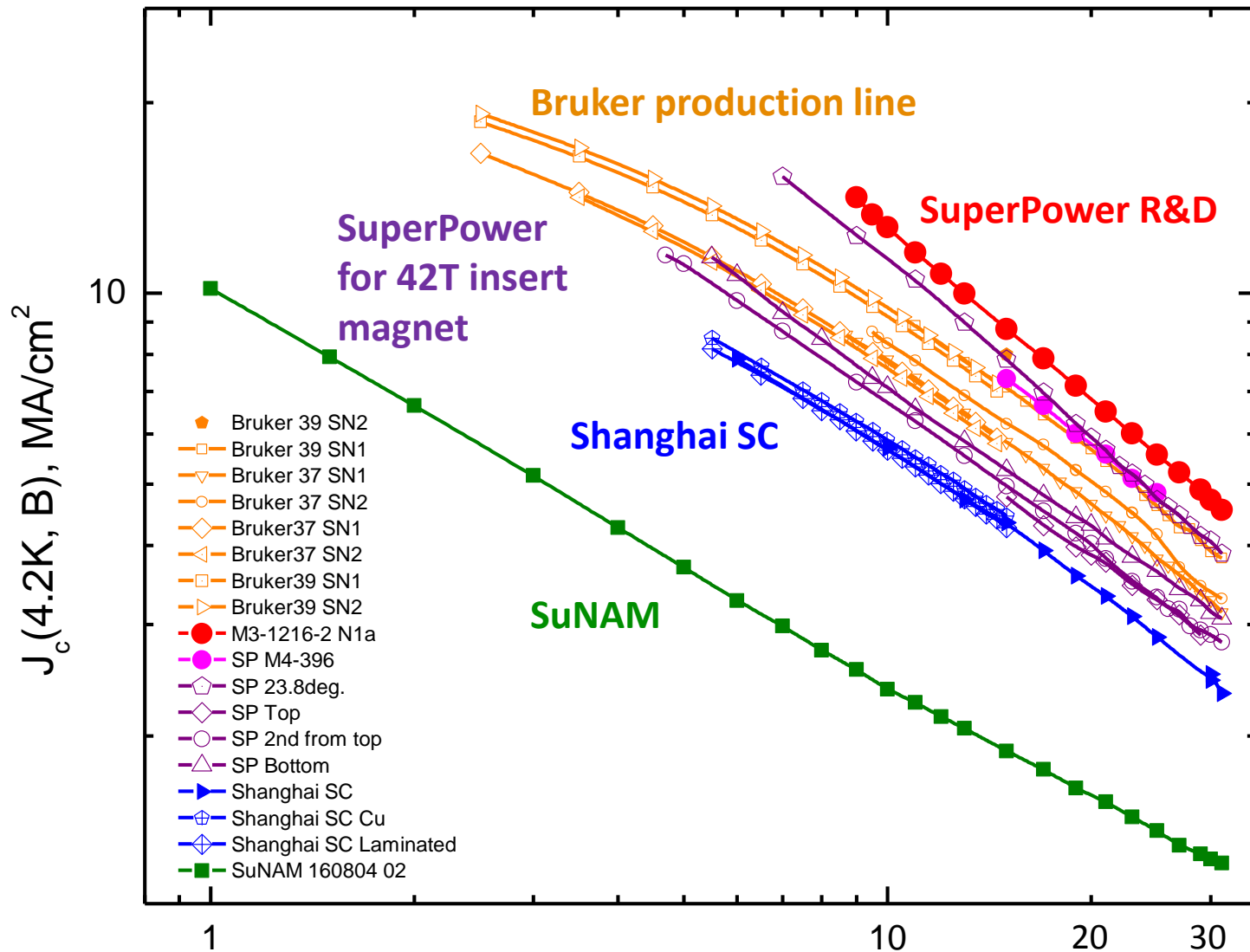
1 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 338.0 ° Signal A = SE2 ZEISS 1540 XB
Mag = 12.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 14:27:43
WD = 10.0 mm FIB Image Probe = 30KV-50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.6 % Date 10 Feb 2017
Pixel Size = 24.41 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 28.9 % File Name = SuperPower_2nd_fro

SuNAM



2 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 335.0 ° Signal A = SE2 ZEISS 1540 XB
Mag = 12.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time 16:16:06
WD = 10.0 mm FIB Image Probe = 30KV-50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.3 % Date 9 Feb 2017
Pixel Size = 24.41 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV-50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 28.6 % File Name = SuNAM_160804_01

Comparison transport $J_c(4.2K, B)$ for ReBCO tapes from different manufacturers

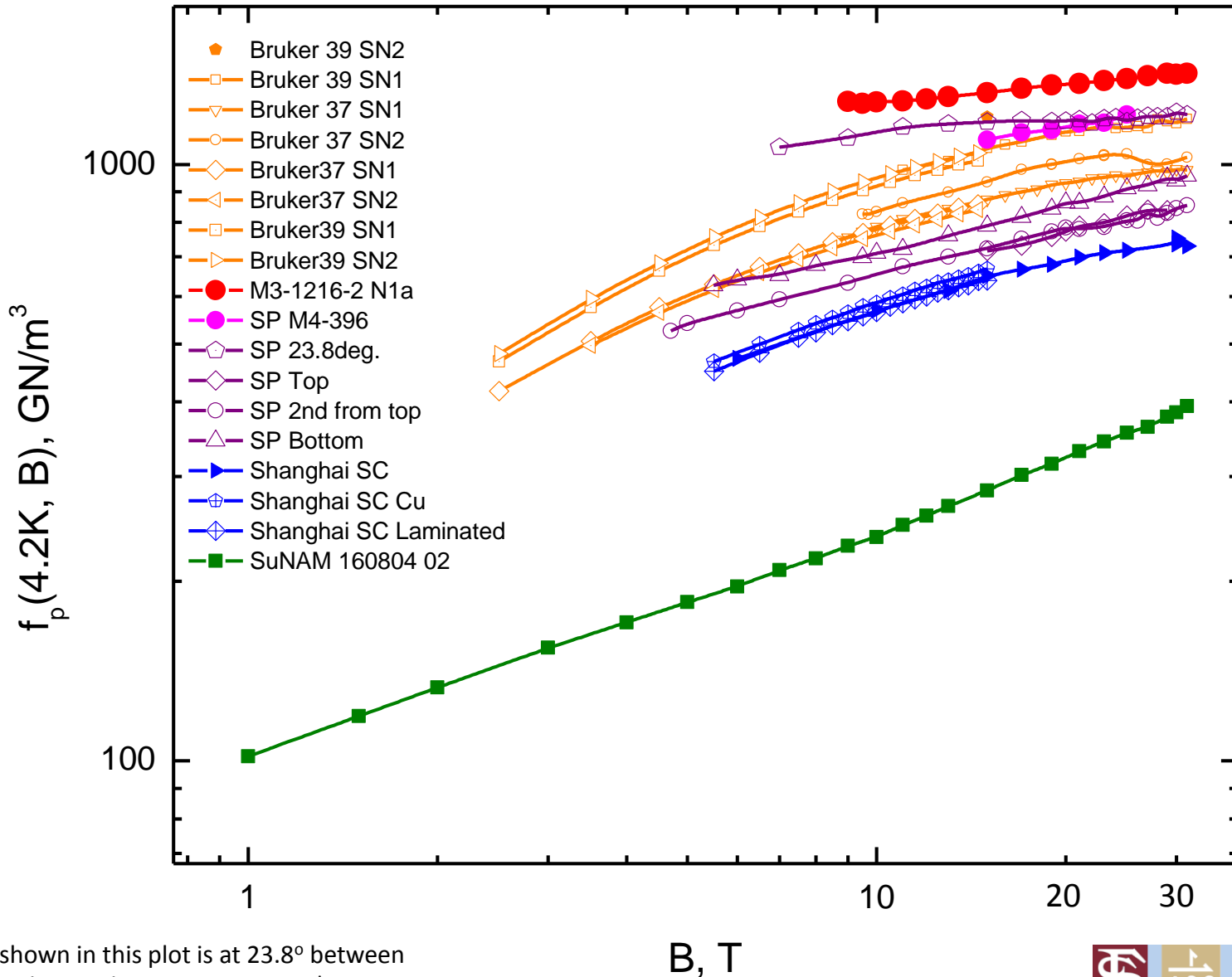


One tape shown in this plot is at 23.8° between B and tape plane, other tapes are at B_{||} tape orientation

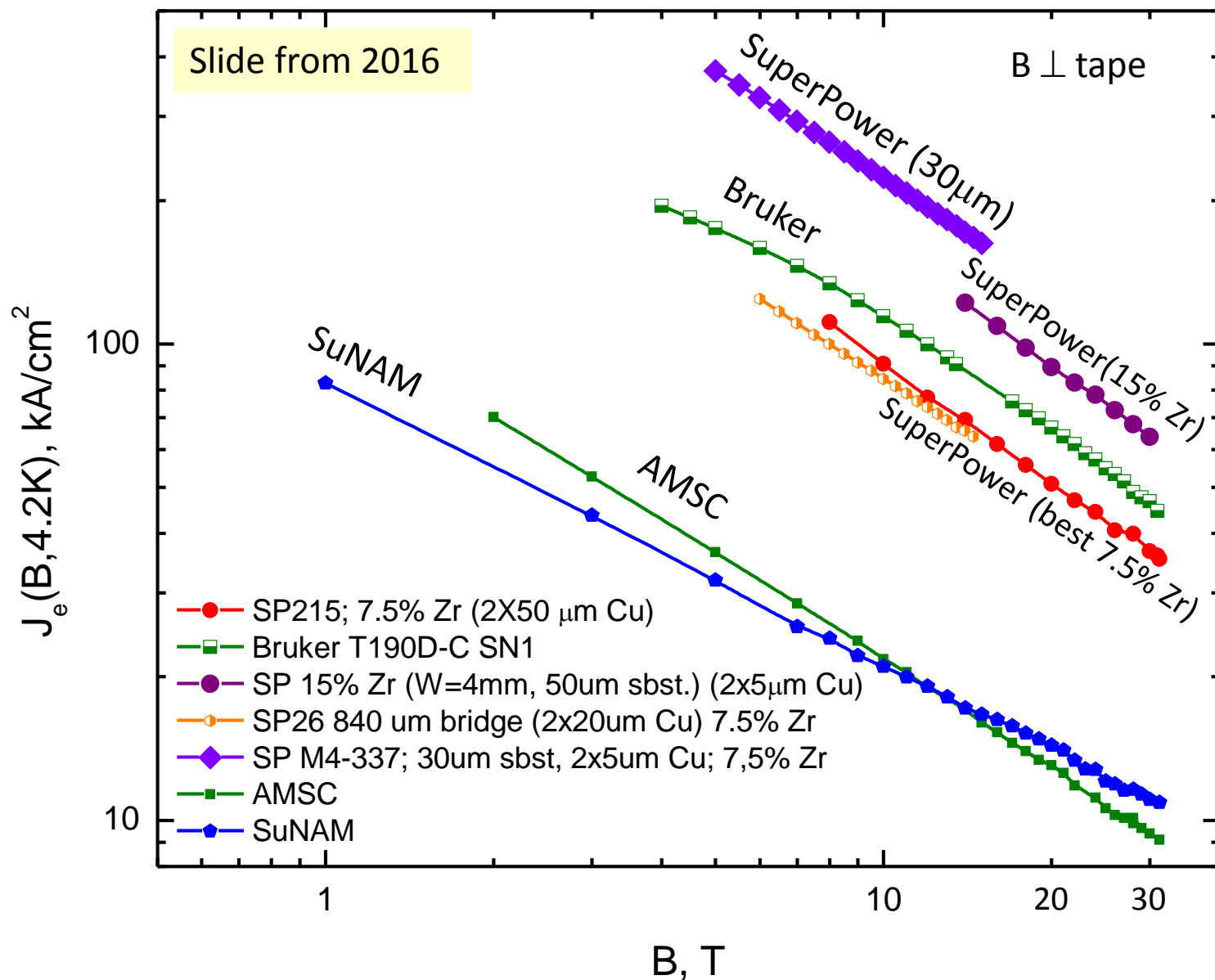
B, T

Comparison transport $f_p(4.2K, B)$ for ReBCO tapes from different manufacturers

SuperPower R&D sample show the largest $f_p(B)$

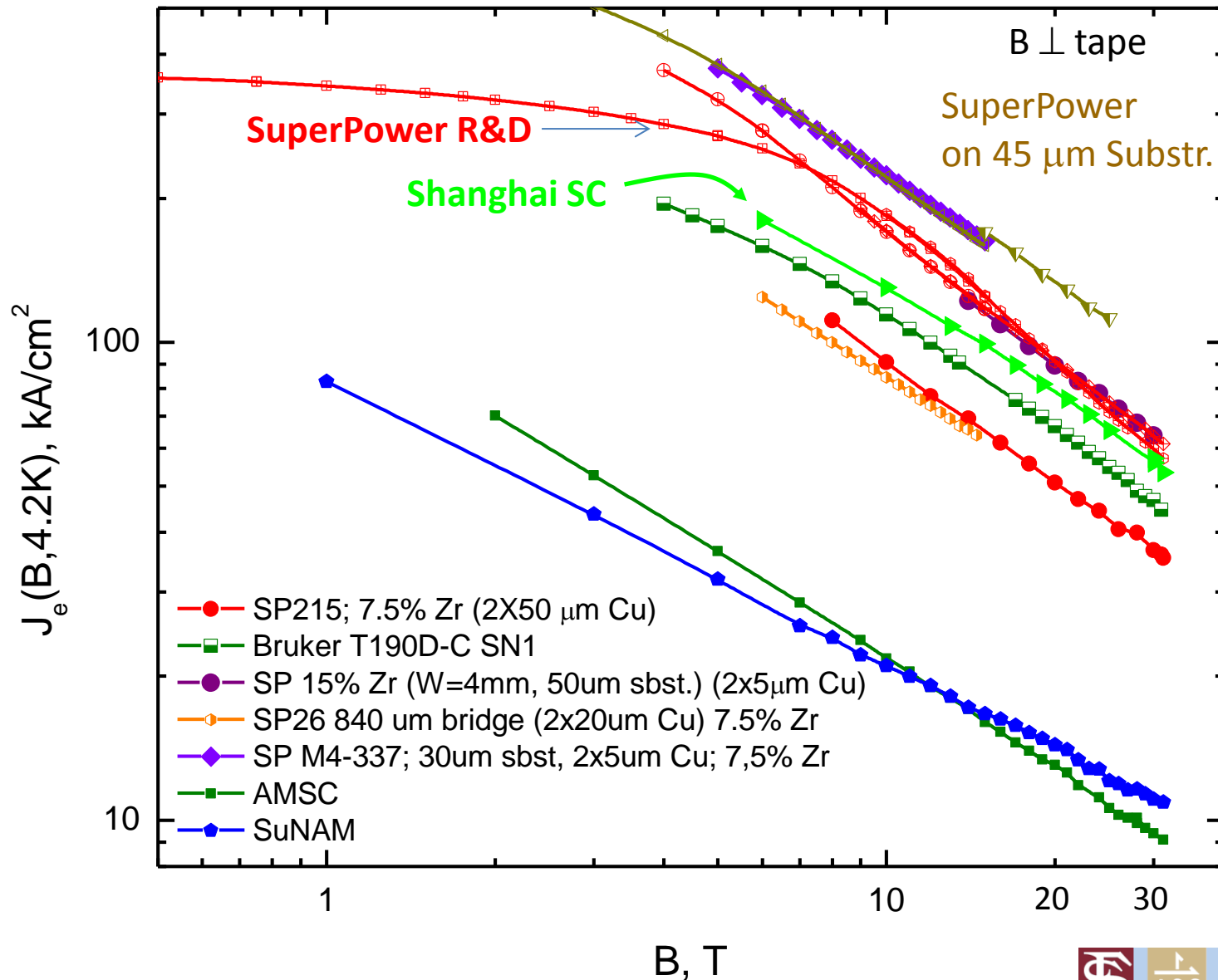


Highest J_e detected for SuperPower Inc. ReBCO tape with 7.5% Zr
4 mm wide, with 30 μm substrate with 2x5 μm thick stabilizer layer Cu



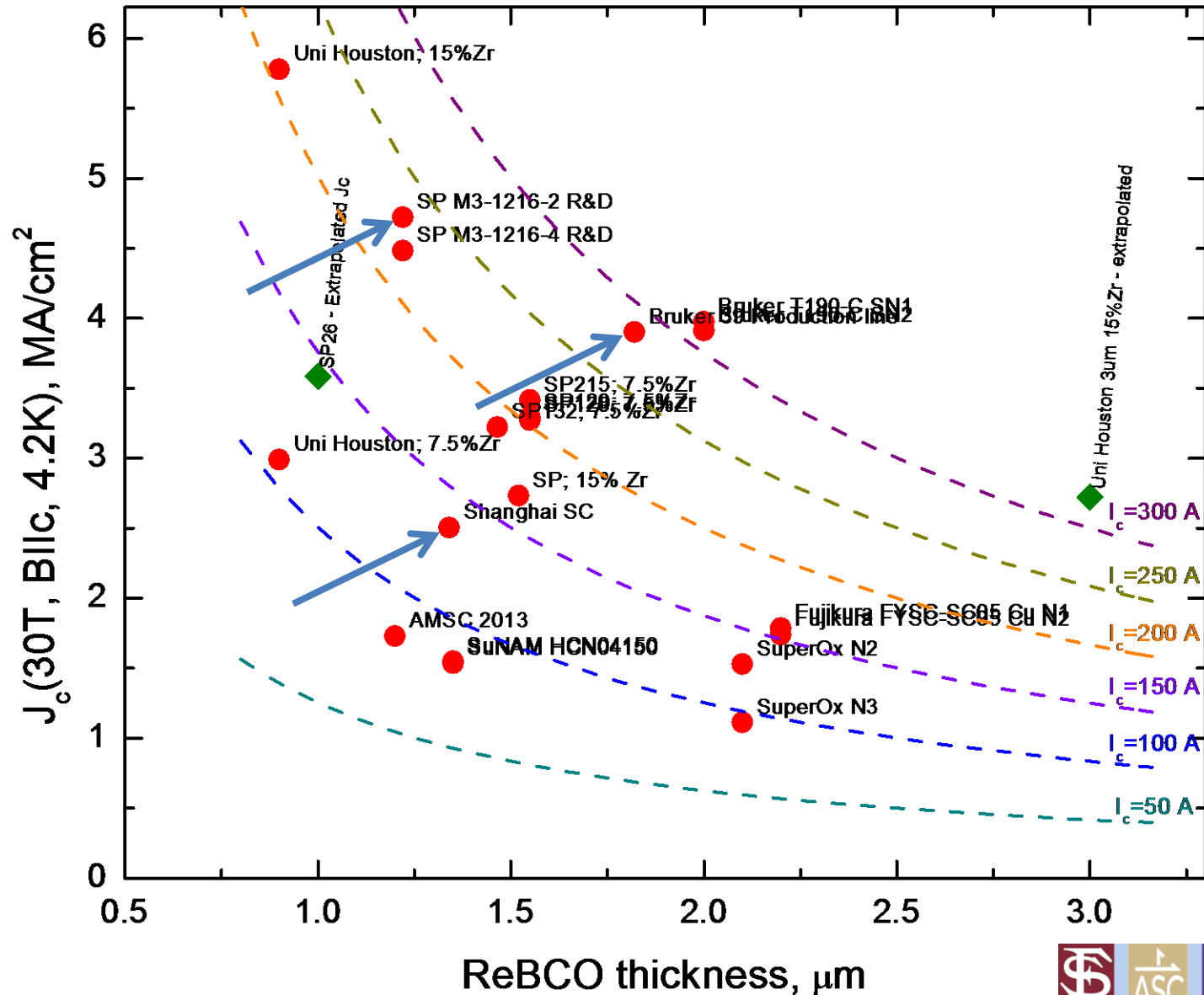
SuperPower Inc. achieved record high J_e (4.2K, B)

for tape with 45 μm substrate



Transport $J_c(30T, 4K, \text{BiIc})$ vs. ReBCO thickness

Bruker production line tape has highest $I_c(30T, 4K)$ among commercially available



Critical current of Cu and Steel coated SuNAM tapes
measured in magnetic fields up to 31.2 T at 4.2K

Short samples for in-field I_c measurements with fixed probe

Samples SuNAM 2016 production line tapes:
35 mm long for resistive magnet,
45 mm long for superconducting magnet

4 mm wide tapes glued on G-10 substrate

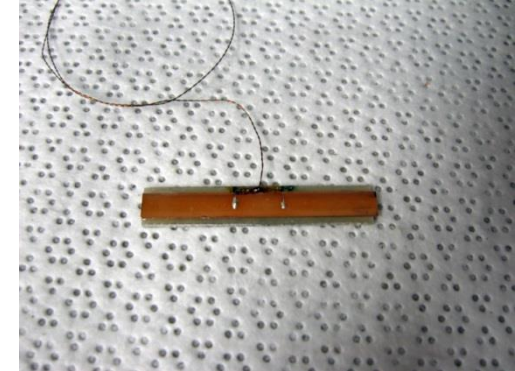
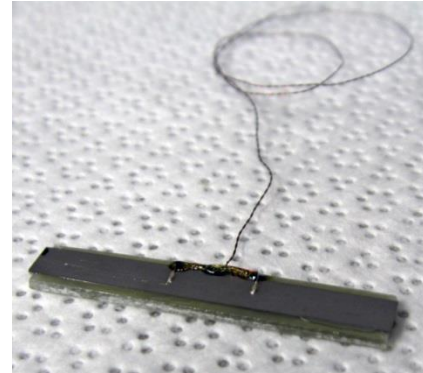
$I_c(77K; SF) > 150$ A

STS coated - $< 5 \mu\text{m}$ on top of $< 5 \mu\text{m}$ Cu

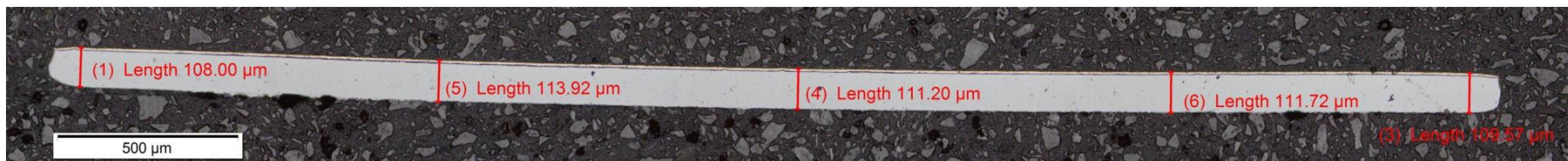
$I_c(77K; SF) > 200$ A

Cu coating $< 5 \mu\text{m}$ on each side

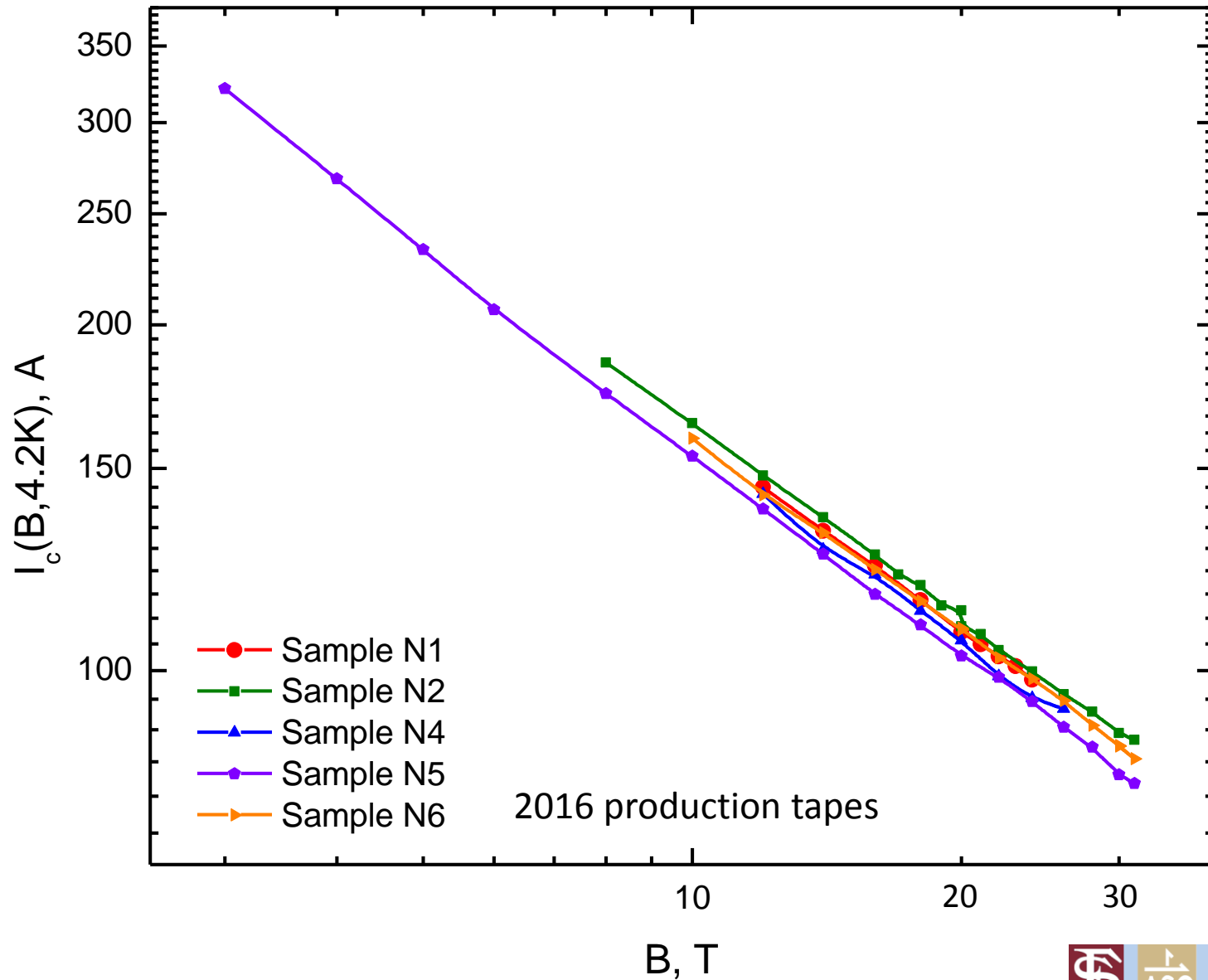
About $100 \mu\text{m}$ thick substrate



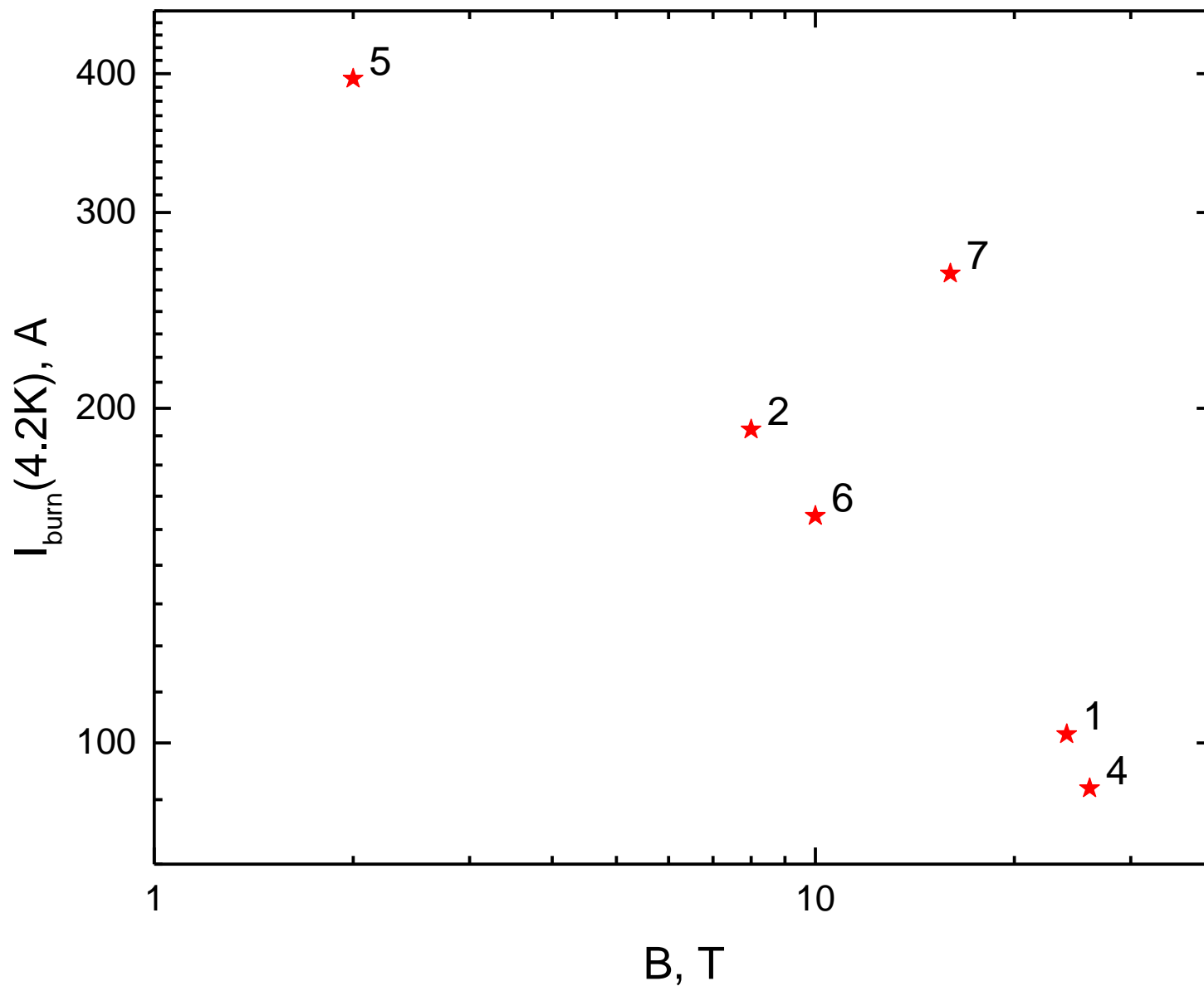
Polished cross section of steel coated tape



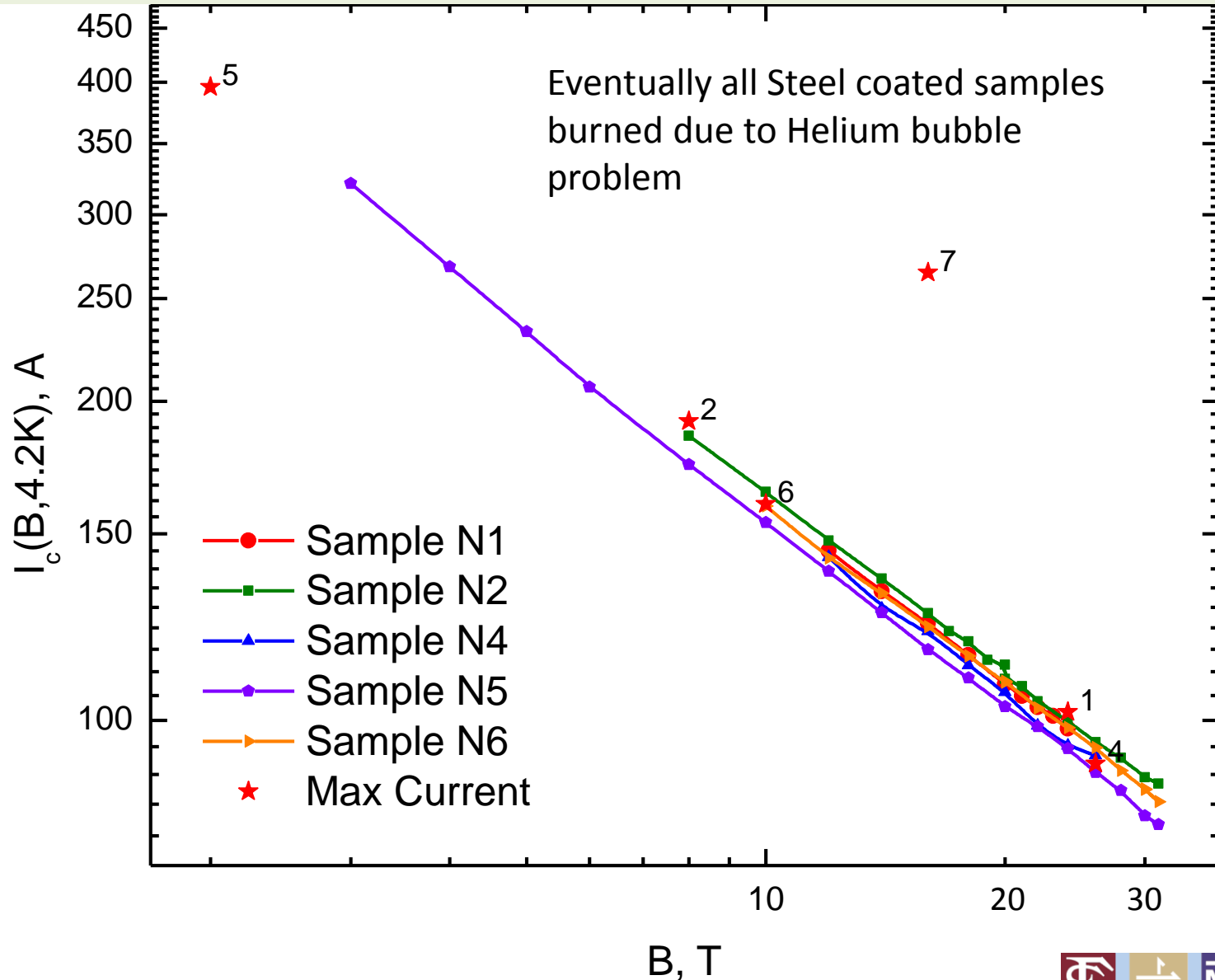
$I_c(B)$ for Steel Coated SuNAM 4 mm wide tapes at 4.2 K measured in resistive magnet (cell 7)



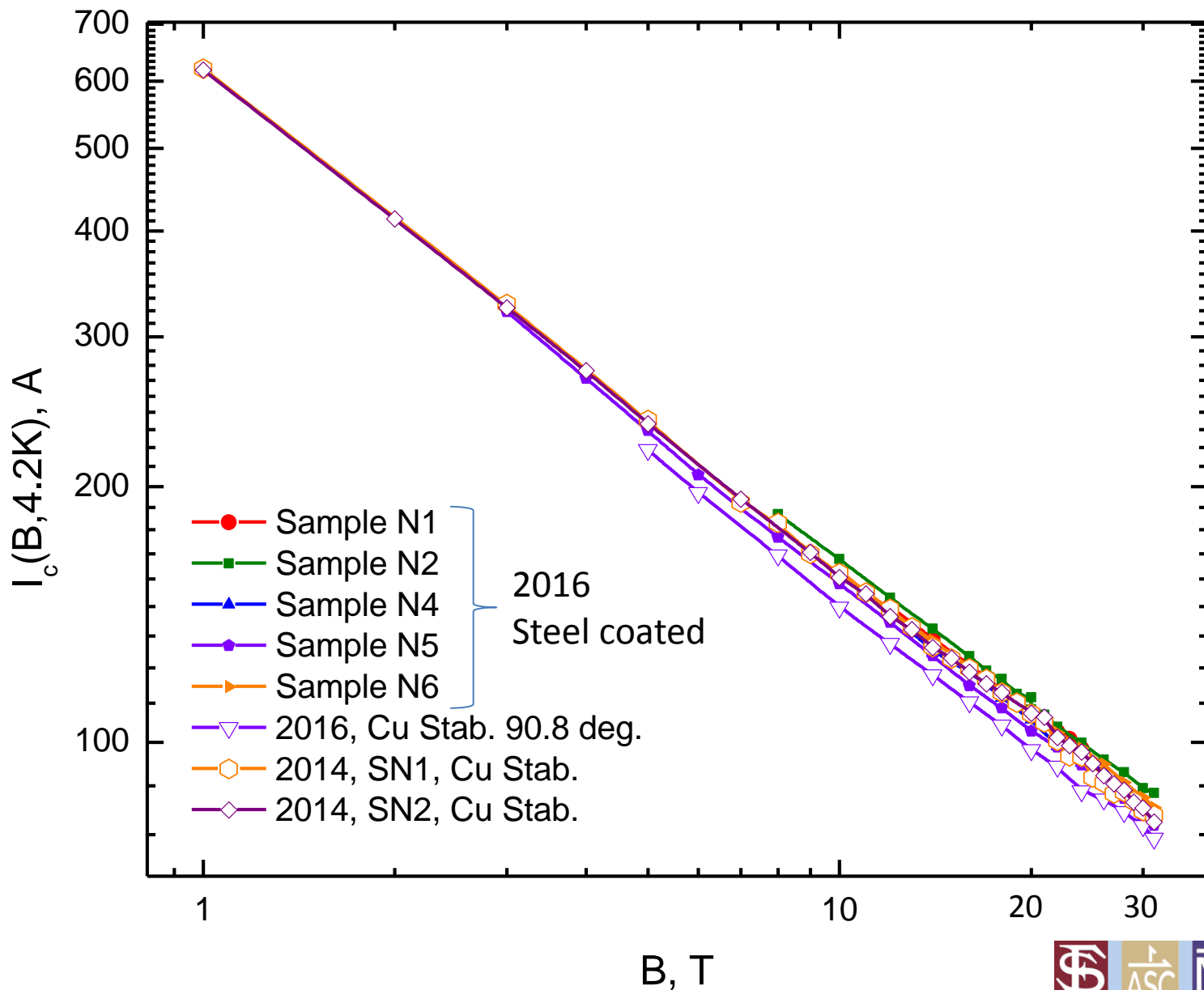
Current and magnetic field values at which samples were burned



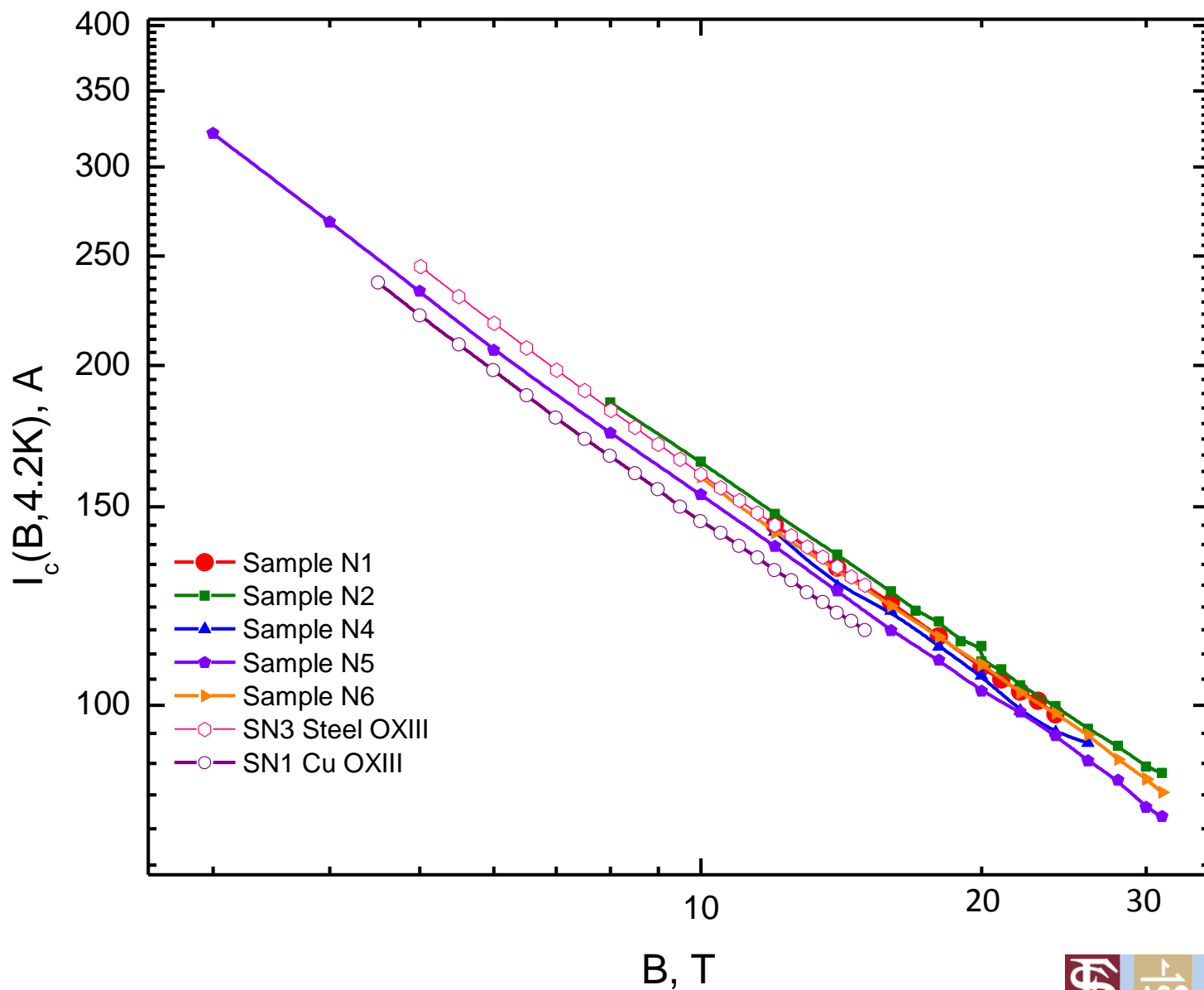
For steel coated samples burning currents coincides with critical currents



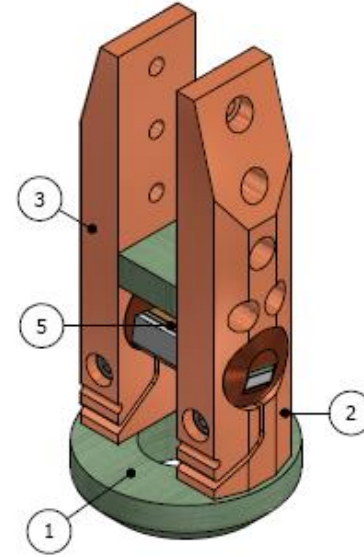
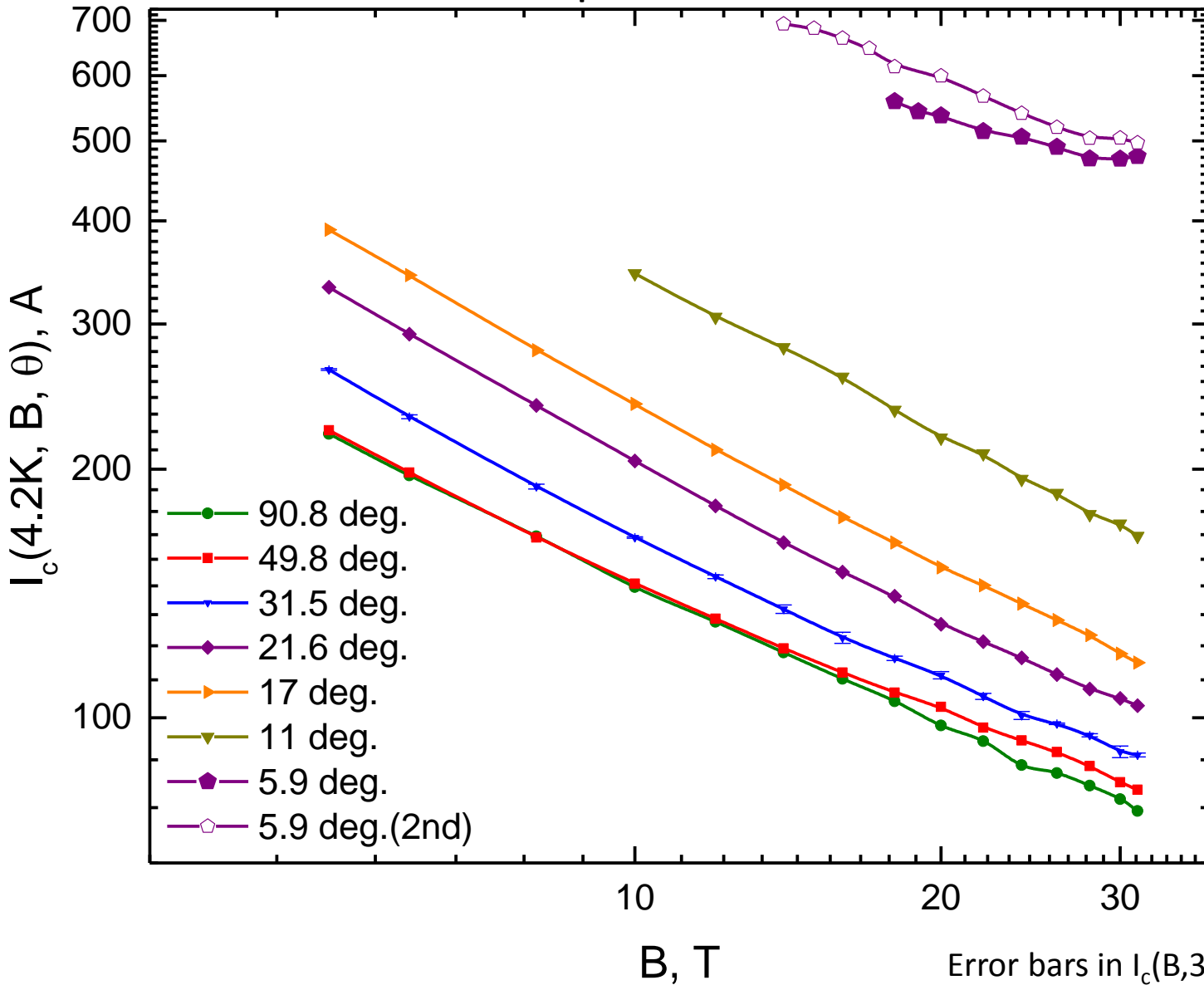
Good match of I_c values for Cu coated and Steel coated tapes measured in resistive magnets



Good match of data measured in superconducting (OXIII) and resistive (cell 7) magnets



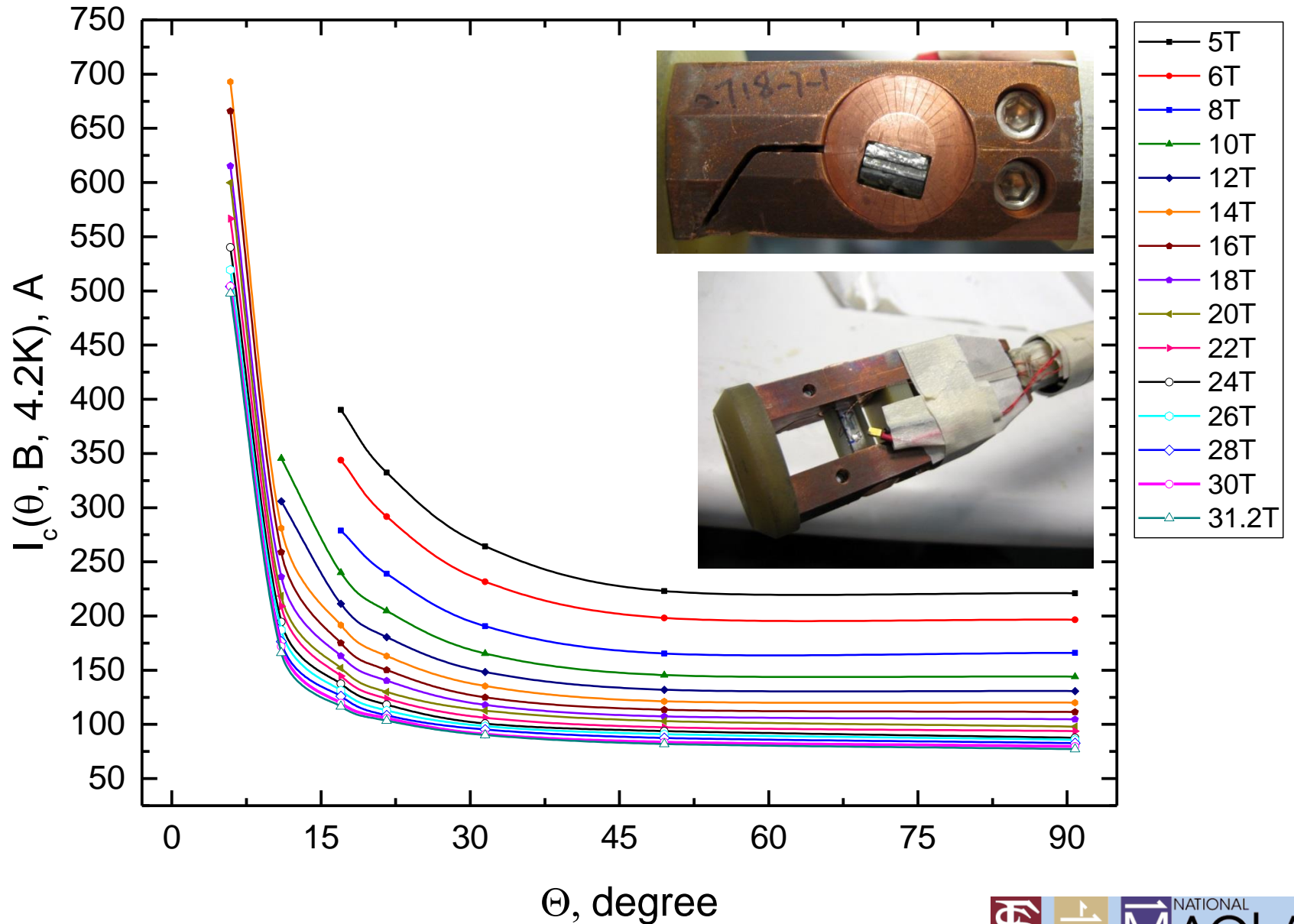
$I_c(4.2K, B)$ of SuNAM Cu coated tape measured for several angles up to 31.2T in cell 7



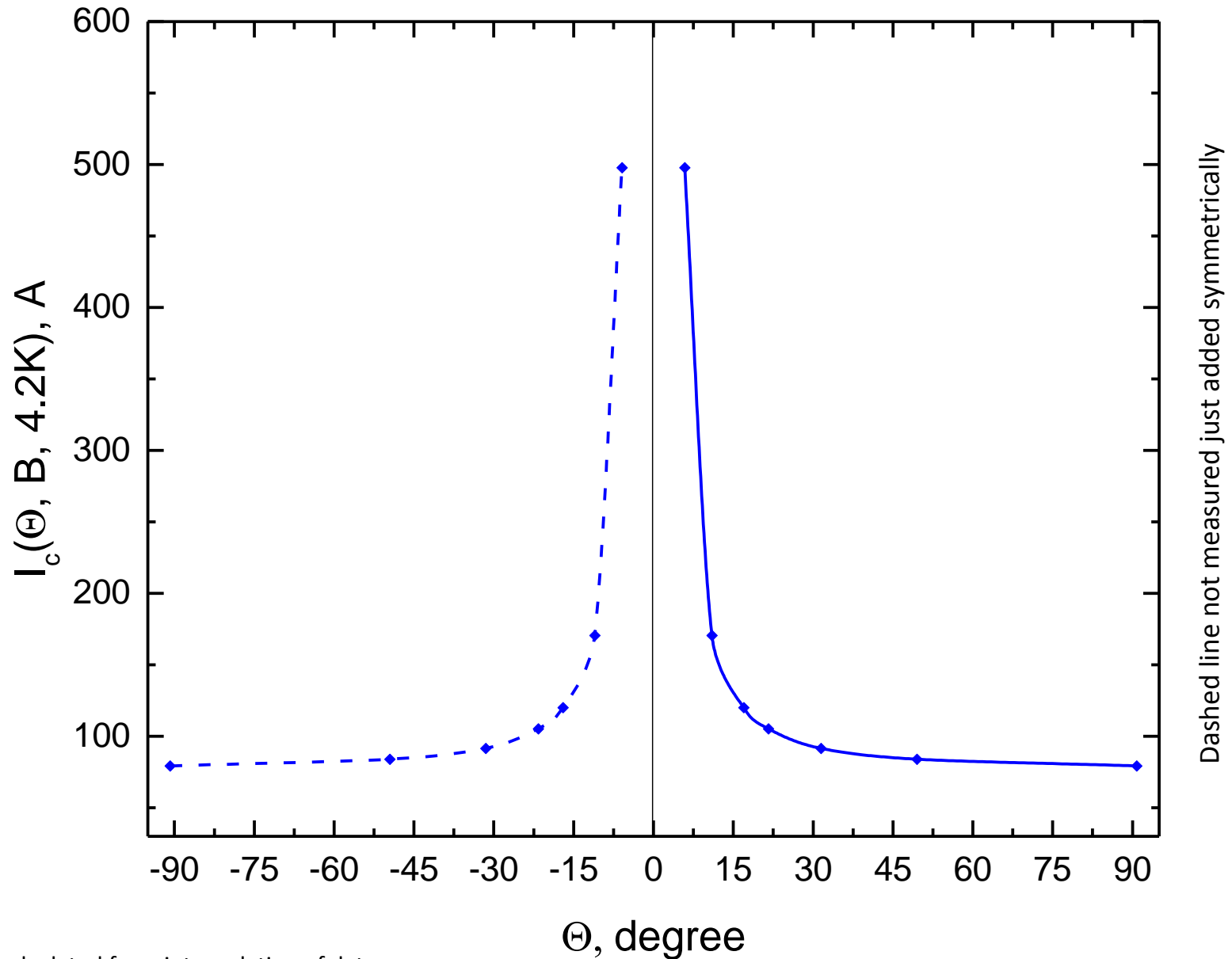
Error bars in $I_c(B, 31.5^\circ)$ are standard deviation

All curves plotted on this graph were measured on one sample (N3) – 4mm wide

$I_c(4.2K, \theta, B)$ of SuNAM Cu coated tape measured up to 31.2T in cell 7

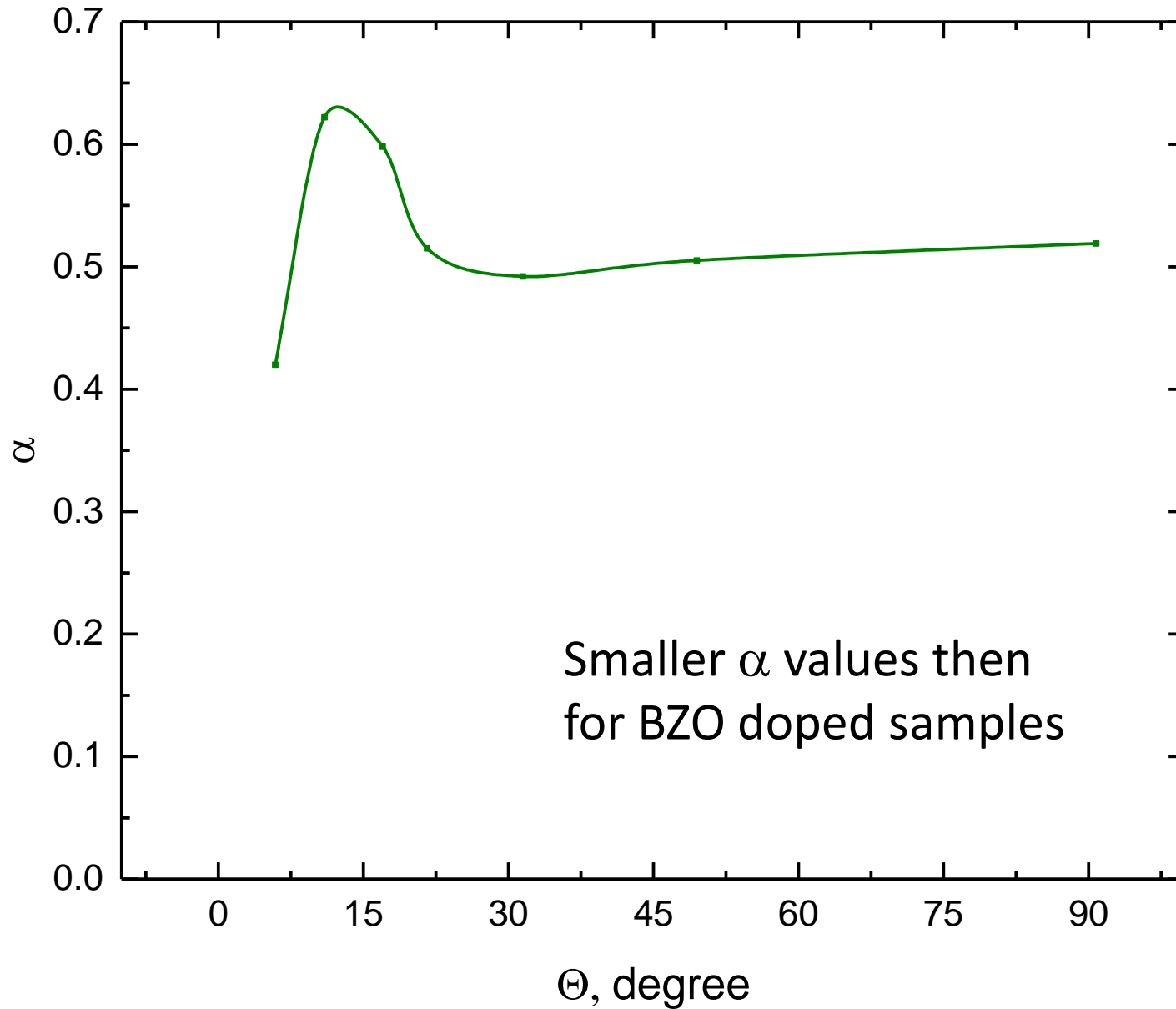


$I_c(4.2K, \theta, 30T)$ with symmetrically added data points for negative θ



I_c at 30T calculated from interpolation of data
between 20t and 31.2T

Slopes of I_c vs. B in log-log scale of SuNAM Cu coated tape
calculated by fitting $I_c \sim B^{-\alpha}$ to 20T .. 31.2T data



Conclusions:

1. Comparison $I_c(B, 4K)$ for SuperPower R&D and production line tapes

- 1) Below $\approx 2T$ 15% Zr tape has lower I_c than 7.5% Zr production line tape
- 2) SEM visualization suggests uniform single phase ReBCO layer visible in FIB patterned cross sections
- 3) ReBCO surface of R&D tapes are free from a-axis grains and CuO grains
- 4) SuperPower achieved very large values of $f_p > 1400 \text{ GN/m}^3$ in R&D 7.5%Zr tapes
- 5) Very different values and field dependence of $f_p(B, 4.2K)$ measured for R&D and production wires in resistive magnet up to 30T
- 6) Detected crossovers in $f_p(B)$ for 7.5% , 15% Zr R&D tapes at 7-8T and 17-20T
- 7) Larger α values corresponds to higher $I_c(4K, 30T)$
- 8) Lift factor grow with % of Zr doping. Additional pinning centers are not effective at 77K, SF

2. Comparison transport properties of ReBCO tapes from different manufacturers

- 1) Bruker production line tapes show higher $I_c(4K, B)$ than SuperPower R&D tapes, but SP R&D J_c values are higher
- 2) Shanghai SC tapes show $I_c(4K, B)$ comparable to SP tapes used for 42T insert
- 3) SuperPower Inc. achieved record high $J_e(4.2K, B)$ for tape with 45mm substrate
- 4) Recent SuperPower R&D tapes grown on the production line are approaching Uni. Houston lab-grown $f_p(B)$ values

Conclusions continuing:

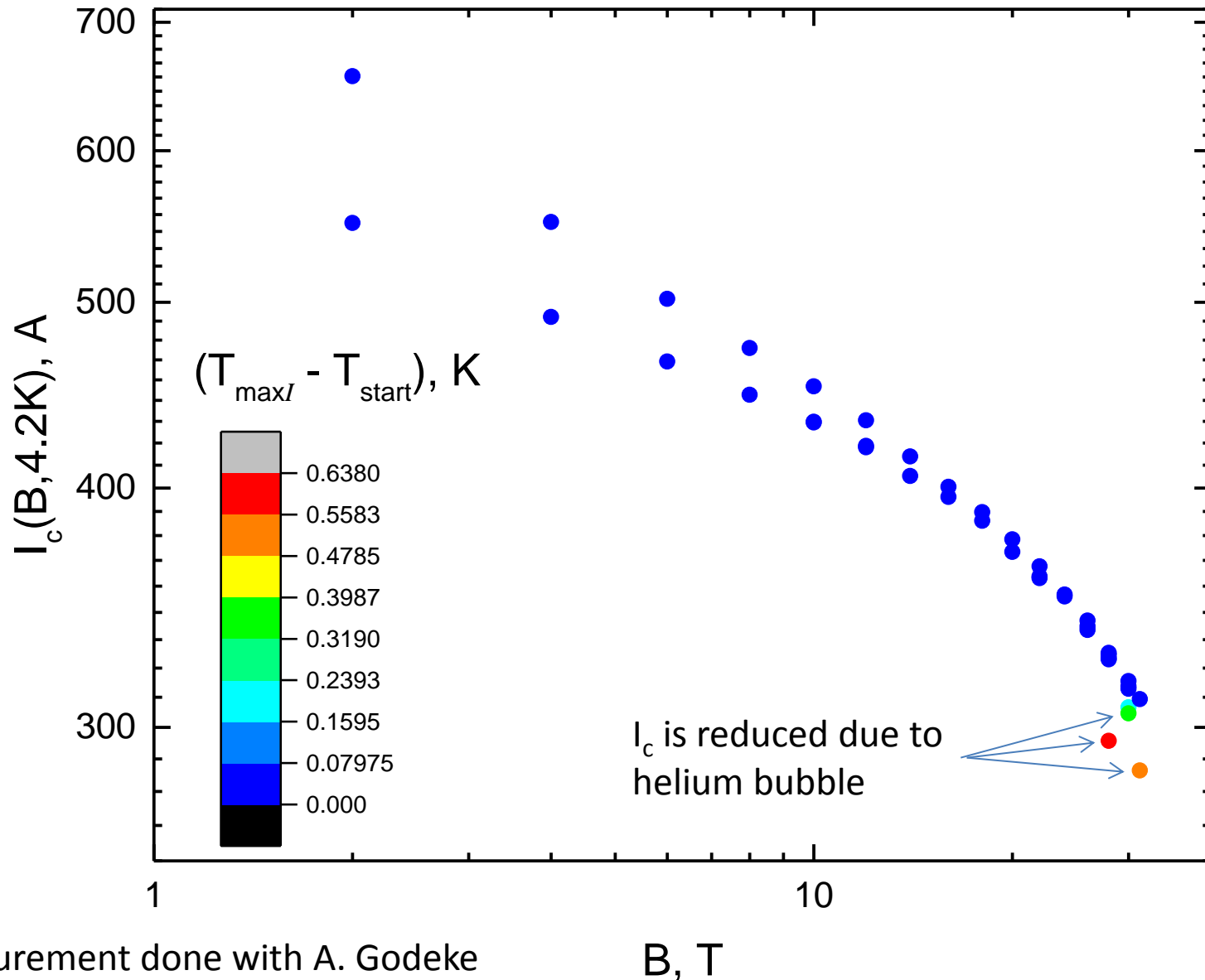
3. I_c of steel coated and Cu plated tapes from SuNAM for making no-insulation magnets

- 1) Above 20T we have to mitigate helium bubble problem (in current setup) for I_c characterization of steel coated samples
- 2) For steel coated samples burning currents coincides with I_c
- 3) **We observed a good match of I_c values for Cu coated and Steel coated tapes measured in SC and resistive magnets**
- 4) Suggestion: improve uniformity of Cu of back side and edges to let current shearing during quench
- 5) Field dependence of $\alpha(B)$ of SuNAM tape qualitatively similar to measured in SuperPower tapes

Additional slides

Example of helium bubble problem:

Transport $I_c(B, 4.2K)$ for short Bi-2223 Sumitomo sample N2, B \perp tape orientation



Measurement done with A. Godeke

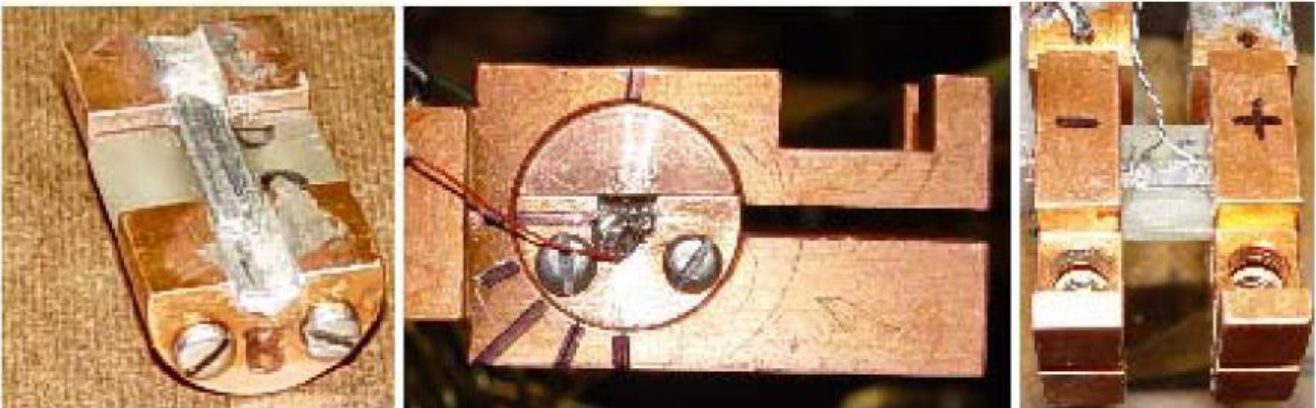
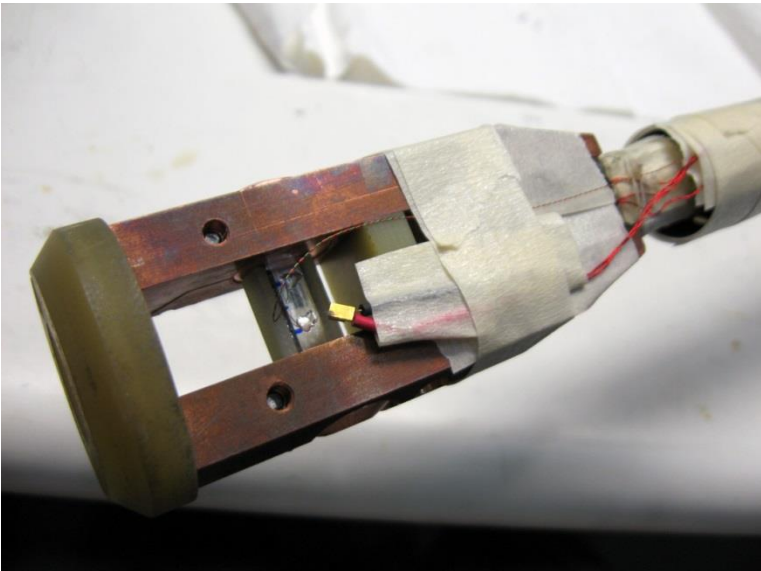


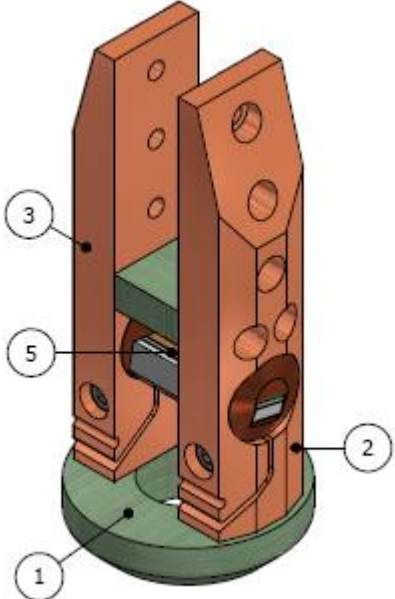
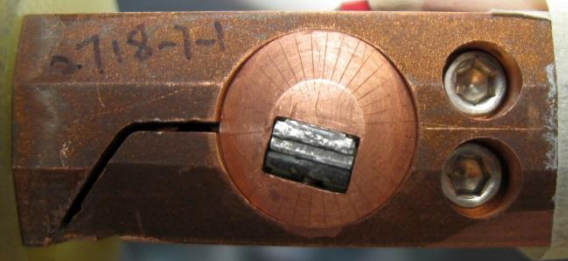
FIGURE 4. Sample holder (left), sample holder within the probe copper lugs (center), and instrumented sample (right).

“Angular Measurements of HTS Critical Current for High Field Solenoids”, D. Turrioni et al.. Advances in Cryogenic Engineering, V. 54, AIP, V. 986, pp. 451-458 (2008).

I_c measured with rotator

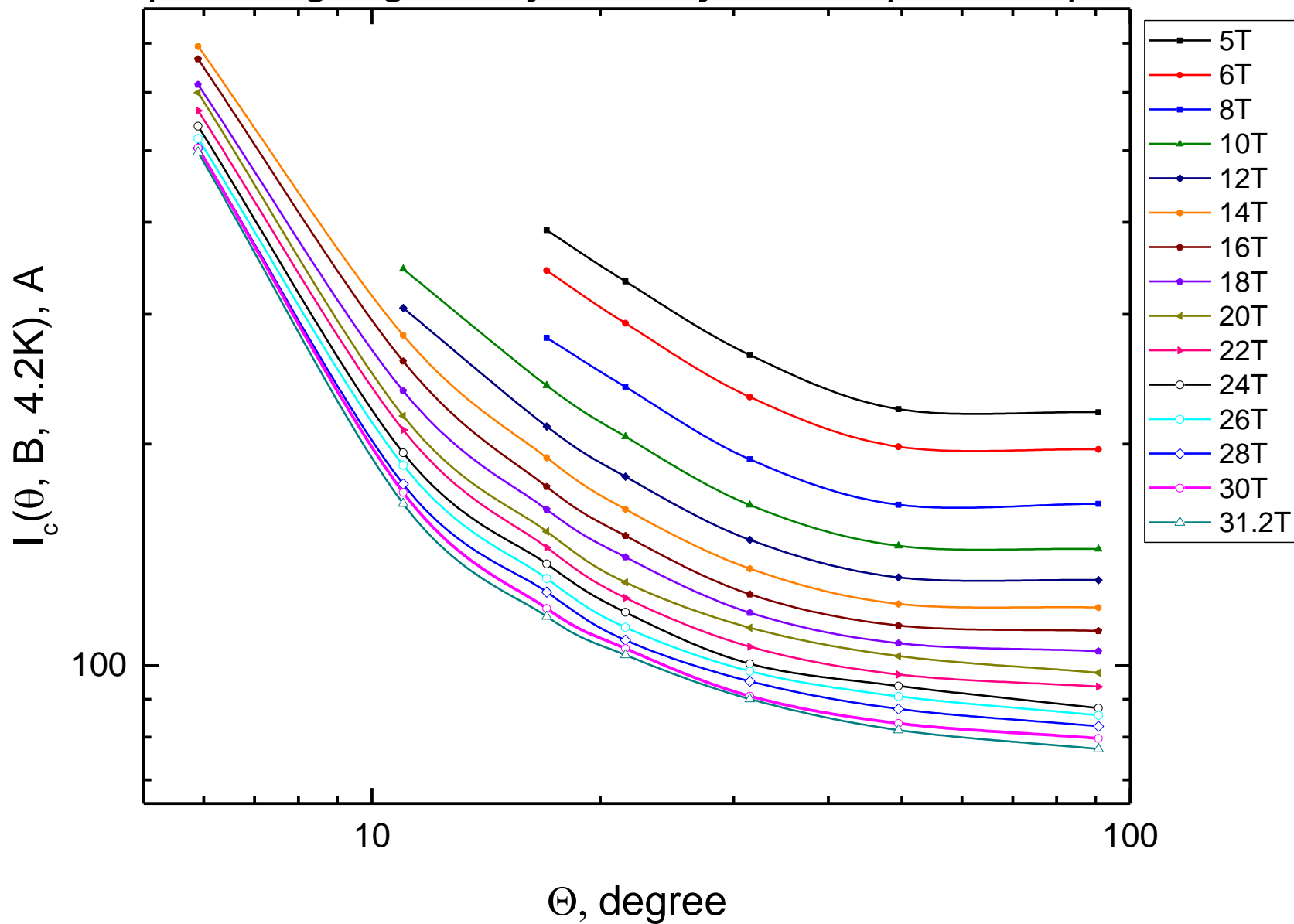


14.8 deg.



$I_c(4.2K, \theta, B)$ of SuNAM Cu coated tape measured up to 31.2T in cell 7

Graph in Log-log scale for data from the previous plot



M3-1211-5

2 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEISS 1540 XIB
Mag = 3.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time :16:52:38
WD = 10.0 mm FIB Image Probe = 30KV:50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.6 % Date :8 Dec 2016
Pixel Size = 97.66 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV:50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 29.0 % File Name = M3_1211_5_001.tif

M3-1176-4

2 μ m EHT = 7.00 kV FIB Mag = 300 K X Beam Shift X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEISS 1540 XIB
Mag = 3.00 K X FIB Lock Mags = Yes Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time :19:56:40
WD = 10.1 mm FIB Image Probe = 30KV:50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.6 % Date :7 Dec 2016
Pixel Size = 97.66 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV:50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 28.6 % File Name = M3_1176_4_n1_00

M3-1216-2 (R&D)

M3-1216-4 (R&D)

Almost defect free ReBCO surface

2 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEISS 1540 XIB
Mag = 3.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time :17:00:58
WD = 10.1 mm FIB Image Probe = 30KV:50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.6 % Date :8 Dec 2016
Pixel Size = 97.66 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV:50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 29.0 % File Name = M3_1216_2_002.tif

2 μ m EHT = 7.00 kV FIB Mag = 300 X Beam Shift X = 0.0 % Scan Rotation = 0.0 ° Signal A = SE2 ZEISS 1540 XIB
Mag = 3.00 K X FIB Lock Mags = No Beam Shift Y = -0.0 % FIB Scan Rot = 0.0 ° Signal B = SE2 Time :15:33:09
WD = 10.0 mm FIB Image Probe = 30KV:50 pA FIB Beam Shift X = 0.00 nm Tilt Angle = 54.0 ° Brightness = 48.6 % Date :8 Dec 2016
Pixel Size = 97.66 nm Aperture Size = 120.0 μ m FIB Milling Probe = 30KV:50 pA FIB Beam Shift Y = 0.00 nm Tilt Corr. = Off Contrast = 29.0 % File Name = M3_1216_4_N1_00

M4-396- 0508

